

# **PCF2129AT**

# Integrated RTC, TCXO and quartz crystal

Rev. 5 — 12 February 2013

**Product data sheet** 

# 1. General description

The PCF2129AT is a CMOS¹ Real Time Clock (RTC) and calendar with an integrated Temperature Compensated Crystal (Xtal) Oscillator (TCXO) and a 32.768 kHz quartz crystal optimized for very high accuracy and very low power consumption. The PCF2129AT has a selectable I²C-bus or SPI-bus, a backup battery switch-over circuit, a programmable watchdog function, a timestamp function, and many other features.

## 2. Features and benefits

- Temperature Compensated Crystal Oscillator (TCXO) with integrated capacitors
- Typical accuracy: ±3 ppm from -15 °C to +60 °C
- Integration of a 32.768 kHz quartz crystal and oscillator in the same package
- Provides year, month, day, weekday, hours, minutes, seconds, and leap year correction
- Timestamp function
  - with interrupt capability
  - detection of two different events on one multilevel input pin (for example, for tamper detection)
- Two line bidirectional 400 kHz Fast-mode I<sup>2</sup>C-bus interface
- 3 line SPI-bus with separate data input and output (maximum speed 6.5 Mbit/s)
- Battery backup input pin and switch-over circuitry
- Battery backed output voltage pin
- Battery low detection function
- Extra power fail detection function with input and output pins
- Power-On Reset Override (PORO)
- Oscillator stop detection function
- Interrupt output (open-drain)
- Programmable 1 second or 1 minute interrupt
- Programmable watchdog timer with interrupt
- Programmable alarm function with interrupt capability
- Programmable square wave open-drain output pin
- Clock operating voltage: 1.2 V to 4.2 V
- Low supply current: typical 0.65 μA at V<sub>DD</sub> = 3.0 V

<sup>1.</sup> The definition of the abbreviations and acronyms used in this data sheet can be found in Section 19.



### Integrated RTC, TCXO and quartz crystal

# 3. Applications

- Electronic metering for electricity, water, and gas
- Timekeeping instruments with high precision
- GPS equipment to reduce time to first fix
- Applications that require an accurate process timing
- Products with long automated unattended operation time

# 4. Ordering information

Table 1. Ordering information

Type number	Package						
	Name	Description	Version				
PCF2129AT	SO20	plastic small outline package; 20 leads; body width 7.5 mm	SOT163-1				

# 4.1 Ordering options

Table 2. Ordering options

Product type number	IC revision	Sales item (12NC)	Delivery form
PCF2129AT/1[1]	1	935288599512	tube, dry pack
		935288599518	tape and reel, 13 inch, dry pack
PCF2129AT/2	2	935295732518	tape and reel, 13 inch, dry pack

<sup>[1]</sup> Not to be used for new designs. Replacement part is PCF2129AT/2.

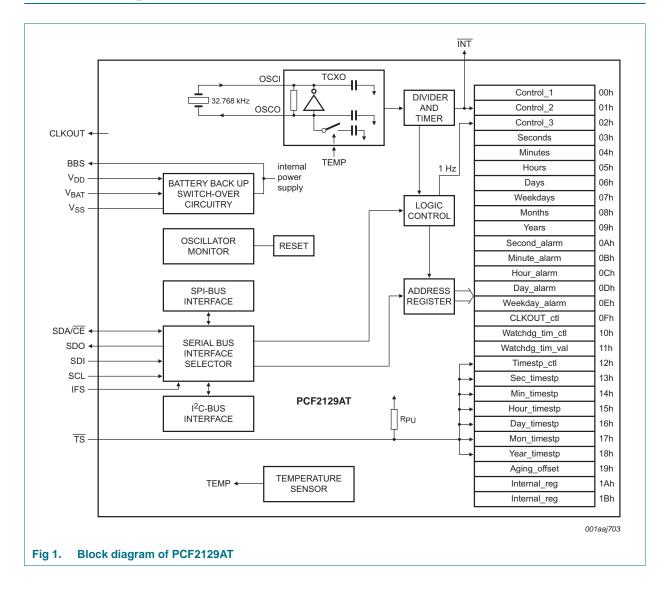
# 5. Marking

Table 3. Marking codes

Product type number	Marking code
PCF2129AT/1	PCF2129AT
PCF2129AT/2	PCF2129AT

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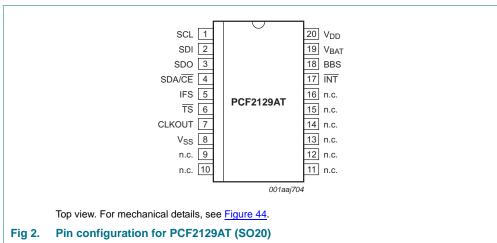
# 6. Block diagram



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# 7. Pinning information

# 7.1 Pinning



# 7.2 Pin description

Table 4. Pin description of PCF2129AT

Symbol	Pin	Description
SCL	1	combined serial clock input for both I $^2\text{C-bus}$ and SPI-bus; may float when SDA/ $\overline{\text{CE}}$ inactive
SDI	2	serial data input for SPI-bus; may float when SDA/CE inactive
SDO	3	serial data output for SPI-bus, push-pull
SDA/CE	4	combined serial data input and output for the I <sup>2</sup> C-bus and chip enable input (active LOW) for the SPI-bus
IFS	5	interface selector input
		connect to pin V <sub>SS</sub> to select the SPI-bus
		connect to pin BBS to select the I <sup>2</sup> C-bus
TS	6	timestamp input (active LOW) with 200 $k\Omega$ internal pull-up resistor (R $_{PU})$
CLKOUT	7	clock output (open-drain)
V <sub>SS</sub>	8	ground supply voltage
n.c.	9 to 16	not connected; do not connect; do not use as feed through
INT	17	interrupt output (open-drain; active LOW)
BBS	18	output voltage (battery backed)
$V_{BAT}$	19	battery supply voltage (backup)
		connect to $V_{\mbox{\footnotesize SS}}$ if battery switch over is not used
$V_{DD}$	20	supply voltage

# 8. Functional description

The PCF2129AT is a Real Time Clock (RTC) and calendar with an on-chip Temperature Compensated Crystal (Xtal) Oscillator (TCXO) and a 32.768 kHz quartz crystal integrated into the same package.

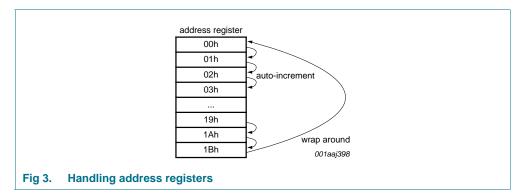
Address and data are transferred by a selectable 400 kHz Fast-mode I<sup>2</sup>C-bus or a 3 line SPI-bus with separate data input and output (see Section 9). The maximum speed of the SPI-bus is 6.5 Mbit/s.

The PCF2129AT has a backup battery input pin and backup battery switch-over circuit which monitors the main power supply. backup battery switch-over circuit automatically switches to the backup battery when a power failure condition is detected (see <a href="Section 8.5.1">Section 8.5.1</a>). Accurate timekeeping is maintained even when the main power supply is interrupted.

A battery low detection circuit monitors the status of the battery (see Section 8.5.3). When the battery voltage drops below a certain threshold value, a flag is set to indicate that the battery must be replaced soon. This ensures the integrity of the data during periods of battery backup.

#### 8.1 Register overview

The PCF2129AT contains an auto-incrementing address register: the built-in address register will increment automatically after each read or write of a data byte up to the register 1Bh. After register 1Bh, the auto-incrementing will wrap around to address 00h (see Figure 3).



- The first three registers (memory address 00h, 01h, and 02h) are used as control registers (see Section 8.2).
- The memory addresses 03h through to 09h are used as counters for the clock function (seconds up to years). The date is automatically adjusted for months with fewer than 31 days, including corrections for leap years. The clock can operate in 12-hour mode with an AM/PM indication or in 24-hour mode (see Section 8.8).
- The registers at addresses 0Ah through 0Eh define the alarm function. It can be selected that an interrupt is generated when an alarm event occurs (see <u>Section 8.9</u>).

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- The register at address 0Fh defines the temperature measurement period and the clock out mode. The temperature measurement can be selected from every 4 minutes (default) down to every 30 seconds (see <u>Table 10</u>). CLKOUT frequencies of 32.768 kHz (default) down to 1 Hz for use as a system clock, a microcontroller clock, and so on, can be chosen (see <u>Table 11</u>).
- The registers at addresses 10h and 11h are used for the watchdog timer functions.
   The watchdog timer has four selectable source clocks allowing for timer periods from less than 1 ms to greater than 4 hours (see <u>Table 33</u>). An interrupt will be generated when the watchdog times out.
- The registers at addresses 12h to 18h are used for the timestamp function. When the trigger event happens, the actual time is saved in the timestamp registers (see Section 8.11).
- The register at address 19h is used for the correction of the crystal aging effect (see Section 8.4.1).
- The registers at addresses 1Ah and 1Bh are for internal use only.
- The registers Seconds, Minutes, Hours, Days, Months, and Years are all coded in Binary Coded Decimal (BCD) format to simplify application use. Other registers are either bit-wise or standard binary.

When one of the RTC registers is written or read, the content of all counters is temporarily frozen. This prevents a faulty writing or reading of the clock and calendar during a carry condition (see Section 8.8.8).

**Table 5.** Register overview

Bit positions labeled as - are not implemented and will return 0 when read. Bits labeled as T must always be written with logic 0. Bits labeled as X are undefined at power-on and unchanged by subsequent resets.

Address	Register name	Bit								
	7		6	5	4	3	2	1	0	
Control r	egisters	'			1	'	'			
00h	Control_1	EXT_ TEST	Т	STOP	TSF1	POR_ OVRD	12_24	MI	SI	0000 0000
01h	Control_2	MSF	WDTF	TSF2	AF	Т	TSIE	AIE	Т	0000 0000
02h	Control_3	PWRMN	IG[2:0]		BTSE	BF	BLF	BIE	BLIE	0000 0000
Time and	date registers									
03h	Seconds	OSF	SECON	DS (0 to 5	9)					1XXX XXXX
04h	Minutes	-	MINUTE	S (0 to 59	)					- XXX XXX
05h	Hours	-	-	- AMPM HOURS (1 to 12) in 12 h mode						XX XXX
				XX XXX						
06h	Days	-	-	DAYS (1	to 31)					XX XXX
07h	Weekdays	-	-	-	-	-	WEEKD	DAYS (0	to 6)	XXX
08h	Months	-	-	-	MONTH	IS (1 to 12	)			X XXXX
09h	Years	YEARS	(0 to 99)							XXXX XXXX
Alarm reg	gisters									
0Ah	Second_alarm	AE_S	SECON	D_ALARM	l (0 to 59)					1XXX XXXX
0Bh	Minute_alarm	AE_M	MINUTE	_ALARM	(0 to 59)					1XXX XXXX
0Ch	Hour_alarm	AE_H	-	AMPM	HOUR_	ALARM (1	to 12) in	12 h mo	de	1 - XX XXX
				HOUR_A	HOUR_ALARM (0 to 23) in 24 h mode					1 - XX XXX
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 Table 5.
 Register overview ...continued

Bit positions labeled as - are not implemented and will return 0 when read. Bits labeled as T must always be written with logic 0. Bits labeled as X are undefined at power-on and unchanged by subsequent resets.

Address	Register name	Bit	Reset value									
		7	6	5	4	3	2	1	0			
0Dh	Day_alarm	AE_D	-	DAY_AL	ARM (1 t	o 31)	'			1 - XX XXXX		
0Eh	Weekday_alarm	AE_W	-	-	-	-	WEE	KDAY_ALA	RM (0 to 6)	1 XXX		
CLKOUT	control register											
0Fh	CLKOUT_ctl	TCR[1:0]		-	-	-	COF[2	2:0]		00 000		
Watchdo	g registers											
10h	Watchdg_tim_ctl	WD_CD	Т	TI_TP	-	-	-	TF[1:0]	]	000 11		
11h	Watchdg_tim_val	WATCHE	G_TIM_\	/AL[7:0]						XXXX XXXX		
Timestan	np registers											
12h	Timestp_ctl	TSM	TSOFF	-	1_0_16	_TIMES	TP[4:0]			00 - X XXXX		
13h	Sec_timestp	-	SECON	D_TIMEST	ΓP (0 to 5	59)				- XXX XXXX		
14h	Min_timestp	-	MINUTE	_TIMESTI	P (0 to 59	9)				- XXX XXXX		
15h	Hour_timestp	-	-	AMPM	XX XXXX							
				HOUR_1	TIMESTP	(0 to 23)	in 24 h n	node		XX XXXX		
16h	Day_timestp	-	-	DAY_TIN	MESTP (1	1 to 31)				XX XXXX		
17h	Mon_timestp	-	-	-	MONTH	H_TIMES	TP (1 to 1	12)		X XXXX		
18h	Year_timestp	YEAR_T	IMESTP (	0 to 99)						XXXX XXXX		
Aging of	set register											
19h	Aging_offset	-	-	-	-	AO[3:0	)]			1000		
Internal r	egisters											
1Ah	Internal_reg	-	-	-	-	-	-	-	-			
1Bh	Internal_reg	_	_	-	-	-	-	-	-			

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# 8.2 Control registers

The first 3 registers of the PCF2129AT, with the addresses 00h, 01h, and 02h, are used as control registers.

### 8.2.1 Register Control\_1

Table 6. Control\_1 - control and status register 1 (address 00h) bit description

Bit	Symbol	Value		Description	Reference
7	EXT_TEST	0	[1]	normal mode	Section 8.13
		1		external clock test mode	
6	Т	0	[2]	unused	-
5	STOP	0	[1]	RTC source clock runs	Section 8.14
		1		RTC clock is stopped;	
				RTC divider chain flip-flops are asynchronously set logic 0;	
				CLKOUT at 32.768 kHz, 16.384 kHz, or 8.192 kHz is still available	
4	TSF1	0	[1]	no timestamp interrupt generated	Section 8.11.1
		1		flag set when TS input is driven to an intermediate level between power supply and ground;	
				flag must be cleared to clear interrupt	
3	POR_OVRD	0	[1]	Power-On Reset Override (PORO) facility disabled;	Section 8.7.2
				set logic 0 for normal operation	
		1		PORO enabled	
2	12_24	0	[1]	24 hour mode selected	Table 19
		1		12 hour mode selected	
1	MI	0	[1]	minute interrupt disabled	Section 8.12.1
		1		minute interrupt enabled	
0	SI	0	[1]	second interrupt disabled	
		1		second interrupt enabled	

<sup>[1]</sup> Default value.

<sup>[2]</sup> When writing to the register this bit always has to be set logic 0.

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# 8.2.2 Register Control\_2

Table 7. Control\_2 - control and status register 2 (address 01h) bit description

Bit	Symbol	Value		Description	Reference
7	MSF	0	[1]	no minute or second interrupt generated	Section 8.12
		1		flag set when minute or second interrupt generated;	
				flag must be cleared to clear interrupt	
6	WDTF	0	[1]	no watchdog timer interrupt or reset generated	Section 8.12.3
		1		flag set when watchdog timer interrupt or reset generated;	
				flag cannot be cleared by command (read-only)	
5	TSF2	0	[1]	no timestamp interrupt generated	Section 8.11.1
		1		flag set when $\overline{TS}$ input is driven to ground;	
				flag must be cleared to clear interrupt	
4	AF	0	[1]	no alarm interrupt generated	Section 8.9.6
		1		flag set when alarm triggered;	
				flag must be cleared to clear interrupt	
3	Т	0	[2]	unused	-
2	TSIE	0	[1]	no interrupt generated from timestamp flag	Section 8.12.5
		1		interrupt generated when timestamp flag set	
1	AIE	0	[1]	no interrupt generated from the alarm flag	Section 8.12.4
		1		interrupt generated when alarm flag set	
0	Т	0	[2]	unused	-

<sup>[1]</sup> Default value.

<sup>[2]</sup> When writing to the register this bit always has to be set logic 0.

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# 8.2.3 Register Control\_3

Table 8. Control\_3 - control and status register 3 (address 02h) bit description

Bit	Symbol	Value		Description	Reference
7 to 5	PWRMNG[2:0]	[1]		control of the battery switch-over, battery low detection, and extra power fail detection functions	Section 8.5
4	BTSE	0	[2]	no timestamp when battery switch-over occurs	<u>Section 8.11.4</u>
		1		time-stamped when battery switch-over occurs	
3	BF	0	[2]	no battery switch-over interrupt generated	Section 8.5.1
		1		flag set when battery switch-over occurs; flag must be cleared to clear interrupt	
2	BLF	0	[2]	battery status ok; no battery low interrupt generated	Section 8.5.3
		1		battery status low; flag cannot be cleared by command	
1	BIE	0	[2]	no interrupt generated from the battery flag (BF)	Section 8.12.6
		1		interrupt generated when BF is set	
0	BLIE	0	[2]	no interrupt generated from battery low flag (BLF)	<u>Section 8.12.7</u>
		1		interrupt generated when BLF is set	

<sup>[1]</sup> Values see <u>Table 14</u>.

<sup>[2]</sup> Default value.

# 8.3 Register CLKOUT\_ctl

Table 9. CLKOUT\_ctl - CLKOUT control register (address 0Fh) bit description

Bit	Symbol	Value	Description
7 to 6	TCR[1:0]	see <u>Table 10</u>	temperature measurement period
5 to 3	-	-	unused
2 to 0	COF[2:0]	see Table 11	CLKOUT frequency selection

#### 8.3.1 Temperature compensated crystal oscillator

The frequency of tuning fork quartz crystal oscillators is temperature-dependent. In the PCF2129AT, the frequency deviation caused by temperature variation is corrected by adjusting the load capacitance of the crystal oscillator.

The load capacitance is changed by switching between two load capacitance values using a modulation signal with a programmable duty cycle. In order to compensate the spread of the quartz parameters every chip is factory calibrated.

The frequency accuracy can be evaluated by measuring the frequency of the square wave signal available at the output pin CLKOUT. However, the selection of  $f_{CLKOUT} = 32.768$  kHz (default value) leads to inaccurate measurements. Accurate frequency measurement occurs when  $f_{CLKOUT} = 16.384$  kHz or lower is selected (see Table 11).

#### 8.3.1.1 Temperature measurement

The PCF2129AT has a temperature sensor circuit used to perform the temperature compensation of the frequency. The temperature is measured immediately after power-on and then periodically with a period set by the temperature conversion rate TCR[1:0] in the register CLKOUT\_ctl.

Table 10. Temperature measurement period

TCR[1:0]		Temperature measurement period
00	<u>[1]</u>	4 min
01		2 min
10		1 min
11		30 seconds

<sup>[1]</sup> Default value.

#### 8.3.2 Clock output

A programmable square wave is available at pin CLKOUT. Operation is controlled by the COF[2:0] control bits in register CLKOUT\_ctl. Frequencies of 32.768 kHz (default) down to 1 Hz can be generated for use as a system clock, microcontroller clock, charge pump input, or for calibrating the oscillator.

CLKOUT is an open-drain output and enabled at power-on. When disabled, the output is high-impedance.

The duty cycle of the selected clock is not controlled, however, due to the nature of the clock generation all but the 32.768 kHz frequencies will be 50 : 50.

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Table 11. CLKOUT frequency selection

COF[2:0]	CLKOUT frequency (Hz)	Typical duty cycle <sup>[1]</sup>
000[2][3]	32768	60 : 40 to 40 : 60
001	16384	50 : 50
010	8192	50 : 50
011	4096	50 : 50
100	2048	50 : 50
101	1024	50 : 50
110	1	50 : 50
111	CLKOUT = high-Z	-

<sup>[1]</sup> Duty cycle definition: % HIGH-level time : % LOW-level time.

<sup>[2]</sup> Default value.

<sup>[3]</sup> The specified accuracy of the RTC can be only achieved with CLKOUT frequencies not equal to 32.768 kHz or if CLKOUT is disabled.

# 8.4 Register Aging\_offset

Table 12. Aging\_offset - crystal aging offset register (address 19h) bit description

Bit	Symbol	Value	Description
7 to 4	-	-	unused
3 to 0	AO[3:0]	see Table 13	aging offset value

#### 8.4.1 Crystal aging correction

The PCF2129AT has an offset register Aging\_offset to correct the crystal aging effects<sup>2</sup>.

The accuracy of the frequency of a quartz crystal depends on its aging. The aging offset adds an adjustment, positive or negative, in the temperature compensation circuit which allows correcting the aging effect.

At 25  $^{\circ}$ C, the aging offset bits allow a frequency correction of typically 1 ppm per AO[3:0] value, from –7 ppm to +8 ppm.

Table 13. Frequency correction at 25 °C, typical

AO[3:0]	ppm		
Decimal	Binary		
0	0000		+8
1	0001		+7
2	0010		+6
3	0011		+5
4	0100		+4
5	0101		+3
6	0110		+2
7	0111		+1
8	1000	<u>[1]</u>	0
9	1001		-1
10	1010		-2
11	1011		-3
12	1100		-4
13	1101		-5
14	1110		-6
15	1111		-7

<sup>[1]</sup> Default value.

For further information please refer to the application note <u>Ref. 3 "AN10857"</u>.

#### 8.5 Power management functions

The PCF2129AT has two power supply pins and one power output pin:

- V<sub>DD</sub> the main power supply input pin
- V<sub>BAT</sub> the battery backup input pin
- BBS battery backed output voltage pin (equal to the internal power supply)

The PCF2129AT has two power management functions implemented:

- Battery switch-over function
- Battery low detection function

The power management functions are controlled by the control bits PWRMNG[2:0] in register Control\_3:

Table 14. Power management control bit description

PWRMNG[2:0]	Function
000	battery switch-over function is enabled in standard mode;
	battery low detection function is enabled
001	battery switch-over function is enabled in standard mode;
	battery low detection function is disabled
010	battery switch-over function is enabled in standard mode;
	battery low detection function is disabled
011	battery switch-over function is enabled in direct switching mode;
	battery low detection function is enabled
100	battery switch-over function is enabled in direct switching mode;
	battery low detection function is disabled
101	battery switch-over function is enabled in direct switching mode;
	battery low detection function is disabled
111	battery switch-over function is disabled, only one power supply $(V_{DD})$ ;
	battery low detection function is disabled

<sup>[1]</sup> Default value.

#### 8.5.1 Battery switch-over function

The PCF2129AT has a backup battery switch-over circuit which monitors the main power supply  $V_{DD}$ . When a power failure condition is detected, it automatically switches to the backup battery.

One of two operation modes can be selected:

- Standard mode: the power failure condition happens when:
   V<sub>DD</sub> < V<sub>BAT</sub> AND V<sub>DD</sub> < V<sub>th(sw)bat</sub>
   V<sub>th(sw)bat</sub> is the battery switch threshold voltage. Typical value is 2.5 V. The battery switch-over in standard mode works only for V<sub>DD</sub> > 2.5 V.
- Direct switching mode: the power failure condition happens when V<sub>DD</sub> < V<sub>BAT</sub>.
   Direct switching from V<sub>DD</sub> to V<sub>BAT</sub> without requiring V<sub>DD</sub> to drop below V<sub>th(sw)bat</sub>

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<sup>[2]</sup> When the battery switch-over function is disabled, the PCF2129AT works only with the power supply V<sub>DD</sub>; V<sub>BAT</sub> must be put to ground and the battery low detection function is disabled.

When a power failure condition occurs and the power supply switches to the battery, the following sequence occurs:

- 1. The battery switch flag BF (register Control\_3) is set logic 1.
- 2. An interrupt is generated if the control bit BIE (register Control\_3) is enabled (see Section 8.12.6).
- 3. If the control bit BTSE (register Control\_3) is logic 1, the timestamp registers store the time and date when the battery switch occurred (see Section 8.11.4).
- 4. The battery switch flag BF is cleared by command; it must be cleared to clear the interrupt.

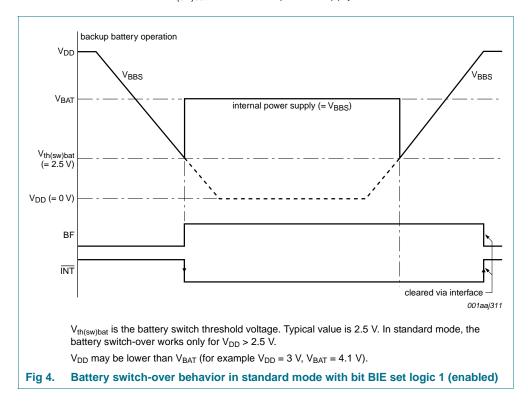
The interface is disabled in battery backup operation:

- Interface inputs are not recognized, preventing extraneous data being written to the device
- Interface outputs are high-impedance

#### 8.5.1.1 Standard mode

If  $V_{DD} > V_{BAT}$  OR  $V_{DD} > V_{th(sw)bat}$ , the internal power supply is  $V_{DD}$ .

If  $V_{DD} < V_{BAT}$  AND  $V_{DD} < V_{th(sw)bat}$ , the internal power supply is  $V_{BAT}$ .



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#### 8.5.1.2 Direct switching mode

If  $V_{DD} > V_{BAT}$  the internal power supply is  $V_{DD}$ .

If  $V_{DD} < V_{BAT}$  the internal power supply is  $V_{BAT}$ .

The direct switching mode is useful in systems where  $V_{DD}$  is higher than  $V_{BAT}$  at all times. This is not recommended if the  $V_{DD}$  and  $V_{BAT}$  values are similar (for example,  $V_{DD} = 3.3 \text{ V}$ ,  $V_{BAT} \geq 3.0 \text{ V}$ ). In direct switching mode, the power consumption is reduced compared to the standard mode because the monitoring of  $V_{DD}$  and  $V_{th(sw)bat}$  is not performed.

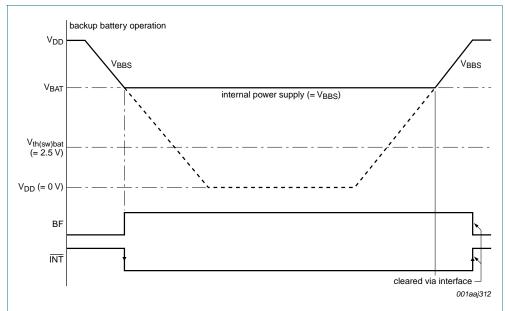


Fig 5. Battery switch-over behavior in direct switching mode with bit BIE set logic 1 (enabled)

#### 8.5.1.3 Battery switch-over disabled: only one power supply (V<sub>DD</sub>)

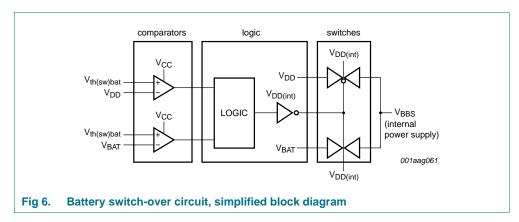
When the battery switch-over function is disabled:

- The power supply is applied on the V<sub>DD</sub> pin
- The V<sub>BAT</sub> pin must be connected to ground
- The internal power supply, available at the output pin BBS, is equal to V<sub>DD</sub>
- The battery flag (BF) is always logic 0

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### 8.5.1.4 Battery switch-over architecture

The architecture of the battery switch-over circuit is shown in Figure 6.



The internal power supply (available on pin BBS) is equal to  $V_{DD}$  or  $V_{BAT}$ . It has to be assured that there are decoupling capacitors on the pins  $V_{DD}$ ,  $V_{BAT}$ , and BBS.

# 8.5.2 Battery backup supply

The  $V_{BBS}$  voltage on the output pin BBS is equal to the internal power supply, depending on the selected battery switch-over function mode:

Table 15. Output pin BBS

Battery switch-over function mode	Conditions	V <sub>BBS</sub> equals
standard	$V_{DD} > V_{BAT} OR V_{DD} > V_{th(sw)bat}$	$V_{DD}$
	$V_{DD} < V_{BAT}$ AND $V_{DD} < V_{th(sw)bat}$	$V_{BAT}$
direct switching	$V_{DD} > V_{BAT}$	$V_{DD}$
	$V_{DD} < V_{BAT}$	$V_{BAT}$
disabled	only V <sub>DD</sub> available, V <sub>BAT</sub> must be put to ground	$V_{DD}$

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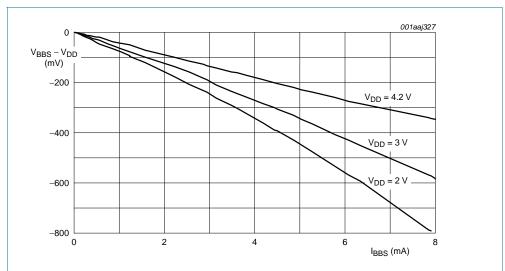


Fig 7. Typical driving capability of V<sub>BBS</sub>: (V<sub>BBS</sub> – V<sub>DD</sub>) with respect to the output load current I<sub>BBS</sub>

The output pin BBS can be used as a supply for external devices with battery backup needs, such as SRAM (see Ref. 3 "AN10857"). For this case, Figure 7 shows the typical driving capability when  $V_{BBS}$  is driven from  $V_{DD}$ .

#### 8.5.3 Battery low detection function

The PCF2129AT has a battery low detection circuit which monitors the status of the battery  $V_{\text{BAT}}$ .

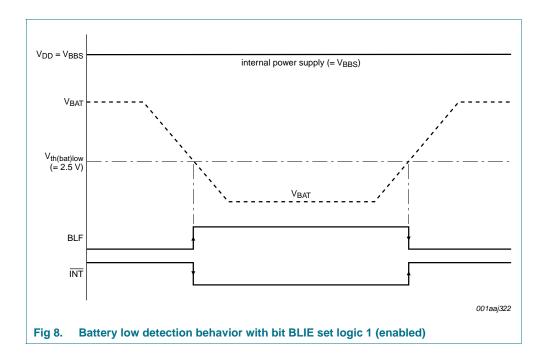
When  $V_{BAT}$  drops below the threshold value  $V_{th(bat)low}$  (typically 2.5 V), the BLF flag (register Control\_3) is set to indicate that the battery is low and that it must be replaced. Monitoring of the battery voltage also occurs during battery operation.

An unreliable battery cannot prevent that the supply voltage drops below  $V_{low}$  (typical 1.2 V) and with that the data integrity gets lost.

When  $V_{BAT}$  drops below the threshold value  $V_{th(bat)low}$ , the following sequence occurs (see Figure 8):

- 1. The battery low flag BLF is set logic 1.
- 2. An interrupt is generated if the control bit BLIE (register Control\_3) is enabled (see Section 8.12.7).
- The flag BLF remains logic 1 until the battery is replaced. BLF cannot be cleared by command. It is cleared automatically by the battery low detection circuit when the battery is replaced.

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# 8.6 Oscillator stop detection function

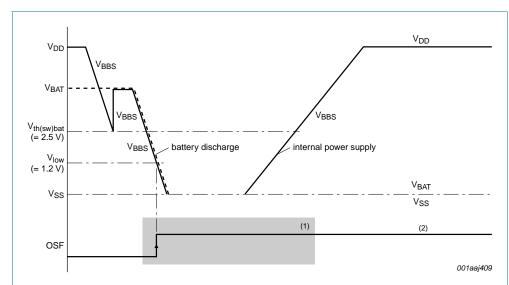
The PCF2129AT has an on-chip oscillator detection circuit which monitors the status of the oscillation: whenever the oscillation stops, a reset occurs and the oscillator stop flag OSF (in register Seconds) is set logic 1.

#### • Power-on:

- a. The oscillator is not running, the chip is in reset (OSF is logic 1).
- b. When the oscillator starts running and is stable after power-on, the chip exits from reset.
- c. The flag OSF is still logic 1 and can be cleared (OSF set logic 0) by command.

#### • Power supply failure:

- a. When the power supply of the chip ( $V_{BBS}$ , see Section 8.5.2) drops below a certain value ( $V_{low}$ ), typically 1.2 V, the oscillator stops running and a reset occurs.
- b. When the power supply returns to normal operation, the oscillator starts running again, the chip exits from reset.
- c. The flag OSF is still logic 1 and can be cleared (OSF set logic 0) by command.



- (1) Theoretical state of the signals since there is no power.
- (2) The oscillator stop flag (OSF), set logic 1, indicates that the oscillation has stopped and a reset has occurred since the flag was last cleared (OSF set logic 0). In this case, the integrity of the clock information is not guaranteed. The OSF flag is cleared by command.

Fig 9. Power failure event due to battery discharge: reset occurs

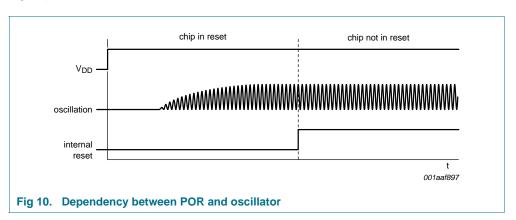
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#### 8.7 Reset function

The PCF2129AT has a Power-On Reset (POR) and a Power-On Reset Override (PORO) function implemented.

#### 8.7.1 Power-On Reset (POR)

The POR is active whenever the oscillator is stopped. The oscillator is also considered to be stopped during the time between power-on and stable crystal resonance (see Figure 10). This time may be in the range of 200 ms to 2 s depending on temperature and supply voltage. Whenever an internal reset occurs, the oscillator stop flag is set (OSF set logic 1).



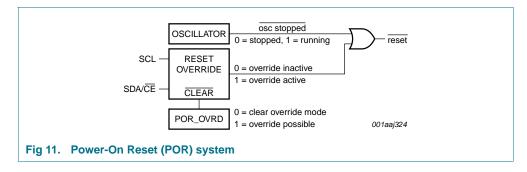
After POR, the following mode is entered:

- 32.768 kHz CLKOUT active
- · Power-On Reset Override (PORO) available to be set
- 24 hour mode is selected
- Battery switch-over is enabled
- Battery low detection is enabled

The register values after power-on are shown in Table 5.

## 8.7.2 Power-On Reset Override (PORO)

The POR duration is directly related to the crystal oscillator start-up time. Due to the long start-up times experienced by these types of circuits, a mechanism has been built in to disable the POR and therefore speed up the on-board test of the device.



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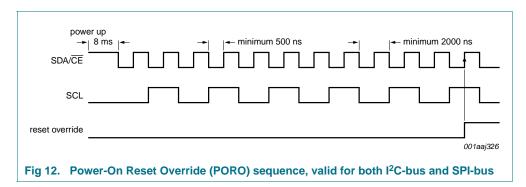
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The setting of the PORO mode requires that POR\_OVRD in register Control\_1 is set logic 1 and that the signals at the interface pins SDA/CE and SCL are toggled as illustrated in Figure 12. All timings shown are required minimum.



Once the override mode is entered, the device is immediately released from the reset state and the set-up operation can commence.

The PORO mode is cleared by writing logic 0 to POR\_OVRD. POR\_OVRD must be logic 1 before a re-entry into the override mode is possible. Setting POR\_OVRD logic 0 during normal operation has no effect except to prevent accidental entry into the PORO mode.

# 8.8 Time and date function

Most of these registers are coded in the Binary Coded Decimal (BCD) format.

### 8.8.1 Register Seconds

Table 16. Seconds - seconds and clock integrity register (address 03h) bit description

Bit	Symbol	Value	Place value	Description
7	OSF	0	-	clock integrity is guaranteed
		1[1]	-	clock integrity is not guaranteed:
				oscillator has stopped and chip reset has occurred since flag was last cleared
6 to 4	SECONDS	0 to 5	ten's place	actual seconds coded in BCD format
3 to 0		0 to 9	unit place	

<sup>[1]</sup> Start-up value.

Table 17. Seconds coded in BCD format

Seconds value in	Upper-dig	Upper-digit (ten's place)			Digit (unit place)			
decimal	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	
00	0	0	0	0	0	0	0	
01	0	0	0	0	0	0	1	
02	0	0	0	0	0	1	0	
:	:	:	:	:	:	:	:	
09	0	0	0	1	0	0	1	
10	0	0	1	0	0	0	0	
:	:	:	:	:	:	:	:	
58	1	0	1	1	0	0	0	
59	1	0	1	1	0	0	1	

# 8.8.2 Register Minutes

Table 18. Minutes - minutes register (address 04h) bit description

Bit	Symbol	Value	Place value	Description
7	-	-	-	unused
6 to 4	MINUTES	0 to 5	ten's place	actual minutes coded in BCD format
3 to 0	-	0 to 9	unit place	_

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## 8.8.3 Register Hours

Table 19. Hours - hours register (address 05h) bit description

		•	•	· · · · · · · · · · · · · · · · · · ·
Bit	Symbol	Value	Place value	Description
7 to 6	-	-	-	unused
12 ho	ur mode[1]			
5 A	AMPM	0	-	indicates AM
		1	-	indicates PM
4	HOURS	0 to 1	ten's place	actual hours coded in BCD format when in
3 to 0		0 to 9	unit place	12 hour mode
24 ho	ur mode[1]			
5 to 4 HOURS		0 to 2	ten's place	actual hours coded in BCD format when in
3 to 0		0 to 9	unit place	24 hour mode

<sup>[1]</sup> Hour mode is set by the bit 12\_24 in register Control\_1.

#### 8.8.4 Register Days

Table 20. Days - days register (address 06h) bit description

Bit	Symbol	Value	Place value	Description
7 to 6	-	-	-	unused
5 to 4	DAYS[1]	0 to 3	ten's place	actual day coded in BCD format
3 to 0	_	0 to 9	unit place	-

<sup>[1]</sup> If the year counter contains a value which is exactly divisible by 4, including the year 00, the RTC compensates for leap years by adding a 29<sup>th</sup> day to February.

### 8.8.5 Register Weekdays

Table 21. Weekdays - weekdays register (address 07h) bit description

Bit	Symbol	Value	Description
7 to 3	-	-	unused
2 to 0	WEEKDAYS	0 to 6	actual weekday value, see Table 22

Although the association of the weekdays counter to the actual weekday is arbitrary, the PCF2129AT will assume that Sunday is 000 and Monday is 001 for the purposes of determining the increment for calendar weeks.

Table 22. Weekday assignments

Day[1]	Bit		
	2	1	0
Sunday	0	0	0
Monday	0	0	1
Tuesday	0	1	0
Wednesday	0	1	1
Thursday	1	0	0
Friday	1	0	1
Saturday	1	1	0

<sup>[1]</sup> Definition may be reassigned by the user.

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#### 8.8.6 Register Months

Table 23. Months - months register (address 08h) bit description

		•	•	
Bit	Symbol	Value	Place value	Description
7 to 5	-	-	-	unused
4	MONTHS	0 to 1	ten's place	actual month coded in BCD format, see
3 to 0		0 to 9	unit place	Table 24

Table 24. Month assignments in BCD format

Month	Upper-digit (ten's place)	Digit (unit place)						
	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0			
January	0	0	0	0	1			
February	0	0	0	1	0			
March	0	0	0	1	1			
April	0	0	1	0	0			
May	0	0	1	0	1			
June	0	0	1	1	0			
July	0	0	1	1	1			
August	0	1	0	0	0			
September	0	1	0	0	1			
October	1	0	0	0	0			
November	1	0	0	0	1			
December	1	0	0	1	0			

#### 8.8.7 Register Years

Table 25. Years - years register (address 09h) bit description

Bit	Symbol	Value	Place value	Description
7 to 4	YEARS	0 to 9	ten's place	actual year coded in BCD format
3 to 0		0 to 9	unit place	

## 8.8.8 Setting and reading the time

Figure 13 shows the data flow and data dependencies starting from the 1 Hz clock tick.

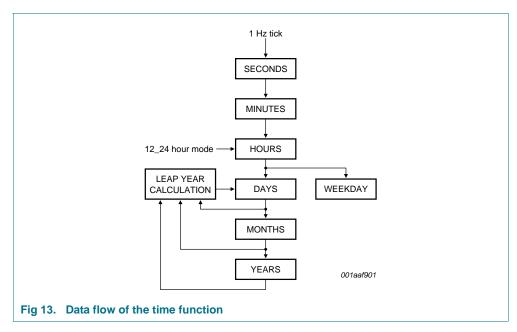
During read/write operations, the time counting circuits (memory locations 03h through 09h) are blocked.

#### This prevents

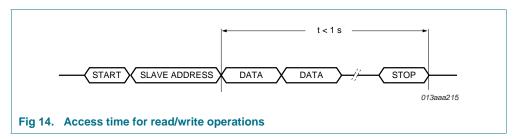
- Faulty reading of the clock and calendar during a carry condition
- Incrementing the time registers during the read cycle

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After this read/write access is completed, the time circuit is released again. Any pending request to increment the time counters that occurred during the read/write access is serviced. A maximum of 1 request can be stored; therefore, all accesses must be completed within 1 second (see <a href="Figure 14">Figure 14</a>).

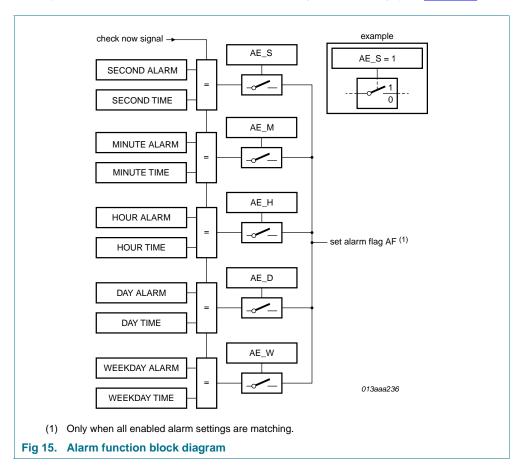


As a consequence of this method, it is very important to make a read or write access in one go, that is, setting or reading seconds through to years should be made in one single access. Failing to comply with this method could result in the time becoming corrupted.

As an example, if the time (seconds through to hours) is set in one access and then in a second access the date is set, it is possible that the time may increment between the two accesses. A similar problem exists when reading. A roll-over may occur between reads thus giving the minutes from one moment and the hours from the next. Therefore it is advised to read all time and date registers in one access.

# 8.9 Alarm function

When one or more of the alarm bit fields are loaded with a valid second, minute, hour, day, or weekday and its corresponding alarm enable bit (AE\_x) is logic 0, then that information is compared with the actual second, minute, hour, day, and weekday (see Figure 15).



The generation of interrupts from the alarm function is described in <u>Section 8.12.4</u>.

#### 8.9.1 Register Second\_alarm

Table 26. Second\_alarm - second alarm register (address 0Ah) bit description

Bit	Symbol	Value	Place value	Description	
7	AE_S	0	-	second alarm is enabled	
		1[1]	-	second alarm is disabled	
6 to 4	SECOND_ALARM	0 to 5	ten's place	second alarm information coded in BCD	
3 to 0		0 to 9 unit place		format	

<sup>[1]</sup> Default value.

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# 8.9.2 Register Minute\_alarm

Table 27. Minute\_alarm - minute alarm register (address 0Bh) bit description

Bit	Symbol	Value	Place value	Description
7	AE_M	0	-	minute alarm is enabled
		1[1]	-	minute alarm is disabled
6 to 4	MINUTE_ALARM	0 to 5	ten's place	minute alarm information coded in BCD
3 to 0		0 to 9	unit place	format

<sup>[1]</sup> Default value.

#### 8.9.3 Register Hour\_alarm

Table 28. Hour\_alarm - hour alarm register (address 0Ch) bit description

Bit	Symbol	Value	Place value	Description
7	AE_H	0	-	hour alarm is enabled
		1[1]	-	hour alarm is disabled
6	-	-	-	unused
12 ho	ur mode[2]			
5	5 AMPM	0	-	indicates AM
		1	-	indicates PM
4	HOUR_ALARM	0 to 1	ten's place	hour alarm information coded in BCD
3 to 0		0 to 9	unit place	format when in 12 hour mode
24 ho	ur mode[2]			
5 to 4	HOUR_ALARM	0 to 2	ten's place	hour alarm information coded in BCD
3 to 0		0 to 9	unit place	format when in 24 hour mode

<sup>[1]</sup> Default value.

# 8.9.4 Register Day\_alarm

Table 29. Day\_alarm - day alarm register (address 0Dh) bit description

Bit	Symbol	Value	Place value	Description
7	AE_D	0	-	day alarm is enabled
		1[1]	-	day alarm is disabled
6	-	-	-	unused
5 to 4	DAY_ALARM	0 to 3	ten's place	day alarm information coded in BCD
3 to 0		0 to 9	unit place	format

<sup>[1]</sup> Default value.

<sup>[2]</sup> Hour mode is set by the bit 12\_24 in register Control\_1.

## 8.9.5 Register Weekday\_alarm

Table 30. Weekday\_alarm - weekday alarm register (address 0Eh) bit description

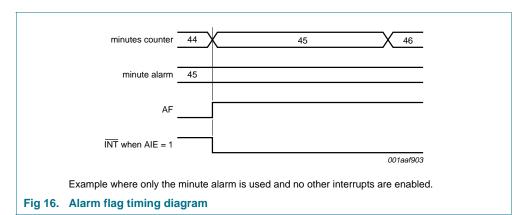
Bit	Symbol	Value	Description
7	AE_W	0	weekday alarm is enabled
		1[1]	weekday alarm is disabled
6 to 3	-	-	unused
2 to 0	WEEKDAY_ALARM	0 to 6	weekday alarm information

<sup>[1]</sup> Default value.

# 8.9.6 Alarm flag

When all enabled comparisons first match, the alarm flag AF (register Control\_2) is set. AF will remain set until cleared by command. Once AF has been cleared, it will only be set again when the time increments to match the alarm condition once more. For clearing the flags, see <a href="Section 8.10.5">Section 8.10.5</a>

Alarm registers which have their alarm enable bit AE\_x at logic 1 are ignored.



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# 8.10 Timer functions

The PCF2129AT has a watchdog timer function. The timer can be switched on and off by using the control bit WD\_CD in the register Watchdg\_tim\_ctl.

The watchdog timer has four selectable source clocks. It can, for example, be used to detect a microcontroller with interrupt and reset capability which is out of control (see Section 8.10.3)

To control the timer function and timer output, the registers Control\_2, Watchdg\_tim\_ctl, and Watchdg\_tim\_val are used.

#### 8.10.1 Register Watchdg\_tim\_ctl

Table 31. Watchdg\_tim\_ctl - watchdog timer control register (address 10h) bit description

Bit	Symbol	Value	Description
7	WD_CD	0[1]	watchdog timer disabled
		1	watchdog timer enabled;
			the interrupt pin $\overline{\text{INT}}$ is activated when timed out
6	Т	0[2]	unused
5	TI_TP	0 <u>[1]</u>	the interrupt pin $\overline{\text{INT}}$ is configured to generate a permanent active signal when MSF (register Control_2) is set
		1	the interrupt pin INT is configured to generate a pulsed signal when MSF flag is set (see Figure 19)
4 to 2	-	-	unused
1 to 0	TF[1:0]		timer source clock for watchdog timer
		00	4.096 kHz
		01	64 Hz
		10	1 Hz
		11 <u>[1]</u>	¹⁄ <sub>60</sub> Hz

<sup>[1]</sup> Default value.

#### 8.10.2 Register Watchdg\_tim\_val

Table 32. Watchdg\_tim\_val - watchdog timer value register (address 11h) bit description

Bit	Symbol	Value	Description
7 to 0	WATCHDG_TIM_VAL[7:0]	00 to FF	timer period in seconds:
			$TimerPeriod = \frac{n}{SourceClockFrequency}$
			where n is the timer value

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<sup>[2]</sup> When writing to the register this bit always has to be set logic 0.

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Table 33. Programmable watchdog timer

TF[1:0]	Timer source clock frequency	Units	Minimum timer period (n = 1)	Units	Maximum timer period (n = 255)	Units
00	4.096	kHz	244	μS	62.256	ms
01	64	Hz	15.625	ms	3.984	S
10	1	Hz	1	S	255	s
11	1/60	Hz	60	S	15300	S

#### 8.10.3 Watchdog timer function

The watchdog timer function is enabled or disabled by the WD\_CD bit of the register Watchdg\_tim\_ctl (see Table 31).

The two bits TF[1:0] in register Watchdg\_tim\_ctl determine one of the four source clock frequencies for the watchdog timer: 4.096 kHz, 64 Hz, 1 Hz, or  $\frac{1}{60}$  Hz (see Table 33).

When the watchdog timer function is enabled, the 8-bit timer in register Watchdg\_tim\_val determines the watchdog timer period (see Table 33).

The watchdog timer counts down from the software programmed 8-bit binary value n in register Watchdg\_tim\_val. When the counter reaches 1, the watchdog timer flag WDTF (register Control\_2) is set logic 1 and an interrupt will be generated.

The counter does not automatically reload.

When WD\_CD is logic 0 (watchdog timer disabled) and the microcontroller unit (MCU) loads a watchdog timer value n, then:

- the flag WDTF is reset
- INT is cleared
- · the watchdog timer starts again

Loading the counter with 0 will:

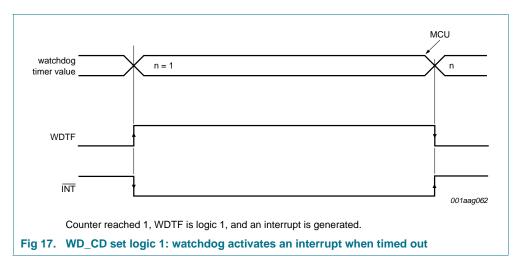
- · reset the flag WDTF
- clear INT
- stop the watchdog timer

**Remark:** WDTF is read only and cannot be cleared by command. WDTF can be cleared by:

- loading a value in register Watchdg\_tim\_val
- reading of the register Control\_2

Writing a logic 0 or logic 1 to WDTF has no effect.

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- When the watchdog timer counter reaches 1, the watchdog timer flag WDTF (register Control\_2) is set logic 1
- When a minute or second interrupt occurs, the minute/second flag MSF (register Control\_2) is set logic 1 (see Section 8.12.1).

#### 8.10.4 Pre-defined timers: second and minute interrupt

PCF2129AT has two pre-defined timers which are used to generate an interrupt either once per second or once per minute. The pulse generator for the minute or second interrupt operates from an internal 64 Hz clock. It is independent of the watchdog timer. Each of these timers can be enabled by the bits SI (second interrupt) and MI (minute interrupt) in register Control 1.

#### 8.10.5 Clearing flags

The flags MSF, AF, and TSFx can be cleared by command. To prevent one flag being overwritten while clearing another, a logic AND is performed during the write access. A flag is cleared by writing logic 0 while a flag is not cleared by writing logic 1. Writing logic 1 will result in the flag value remaining unchanged.

Two examples are given for clearing the flags. Clearing a flag is made by a write command:

- Bits labeled with must be written with their previous values
- Bits labeled with T have to be written with logic 0
- WDTF is read only and has to be written with logic 0

Repeatedly rewriting these bits has no influence on the functional behavior.

Table 34. Flag location in register Control\_2

Register	Bit	Bit									
	7	6	5	4	3	2	1	0			
Control_2	MSF	WDTF	TSF2	AF	Т	-	-	Т			

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Table 35. Example values in register Control\_2

Register	Bit	3it									
	7	6	5	4	3	2	1	0			
Control_2	1	0	1	1	0	0	0	0			

The following tables show what instruction must be sent to clear the appropriate flag.

Table 36. Example to clear only AF (bit 4)

Register	Bit	Bit								
	7	6	5	4	3	2	1	0		
Control_2	1	0	1	0	0	0[1]	0[1]	0		

<sup>[1]</sup> The bits labeled as - have to be rewritten with the previous values.

Table 37. Example to clear only MSF (bit 7)

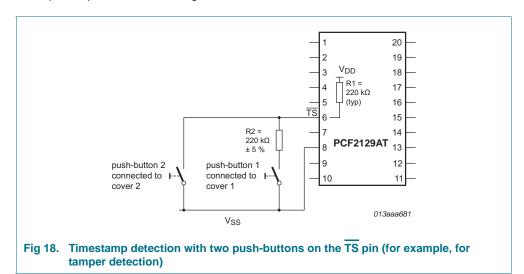
Register	Bit	Bit								
	7	6	5	4	3	2	1	0		
Control_2	0	0	1	1	0	0[1]	0[1]	0		

<sup>[1]</sup> The bits labeled as - have to be rewritten with the previous values.

# 8.11 Timestamp function

The PCF2129AT has an active LOW timestamp input pin  $\overline{TS}$ , internally pulled with an on-chip pull-up resistor to the internal power supply of the device. It also has a timestamp detection circuit which can detect two different events:

- 1. Input on pin TS is driven to an intermediate level between power supply and ground.
- 2. Input on pin  $\overline{TS}$  is driven to ground.



The timestamp function is enabled by default after power-on and it can be switched off by setting the control bit TSOFF (register Timestp\_ctl).

A most common application of the timestamp function is described in Ref. 3 "AN10857".

See Section 8.12.5 for a description of interrupt generation from the timestamp function.

#### 8.11.1 Timestamp flag

- 1. When the TS input pin is driven to an intermediate level between the power supply and ground, then the following sequence occurs:
  - a. The actual date and time are stored in the timestamp registers.
  - b. The timestamp flag TSF1 (register Control\_1) is set.
  - c. If the TSIE bit (register Control\_2) is active, an interrupt on the  $\overline{\text{INT}}$  pin is generated.

The TSF1 flag can be cleared by command. Clearing the flag will clear the interrupt. Once TSF1 is cleared, it will only be set again when a new negative edge on pin  $\overline{\text{TS}}$  is detected.

- 2. When the  $\overline{\mathsf{TS}}$  input pin is driven to ground, the following sequence occurs:
  - a. The actual date and time are stored in the timestamp registers.
  - b. In addition to the TSF1 flag, the TSF2 flag (register Control\_2) is set.
  - c. If the TSIE bit is active, an interrupt on the INT pin is generated.

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The TSF1 and TSF2 flags can be cleared by command; clearing both flags will clear the interrupt. Once TSF2 is cleared, it will only be set again when TS pin is driven to ground once again.

#### 8.11.2 Timestamp mode

The timestamp function has two different modes selected by the control bit TSM (timestamp mode) in register Timestp\_ctl:

- If TSM is logic 0 (default): in subsequent trigger events without clearing the timestamp flags, the last timestamp event is stored
- If TSM is logic 1: in subsequent trigger events without clearing the timestamp flags, the first timestamp event is stored

The timestamp function also depends on the control bit BTSE in register Control\_3, see Section 8.11.4.

# 8.11.3 Timestamp registers

#### 8.11.3.1 Register Timestp\_ctl

Table 38. Timestp\_ctl - timestamp control register (address 12h) bit description

Bit	Symbol	Value	Description
7 TSM		0[1]	in subsequent events without clearing the timestamp flags, the last event is stored
		1	in subsequent events without clearing the timestamp flags, the first event is stored
6 TSOFF		0[1]	timestamp function active
		1	timestamp function disabled
5	-	-	unused
4 to 0	1_O_16_TIMESTP[4:0]		$\frac{1}{16}$ second timestamp information coded in BCD format

<sup>[1]</sup> Default value.

#### 8.11.3.2 Register Sec\_timestp

Table 39. Sec\_timestp - second timestamp register (address 13h) bit description

Bit	Symbol	Value	Place value	Description
7	-	-	-	unused
6 to 4	${\sf SECOND\_TIMESTP}$	0 to 5	ten's place	second timestamp information coded in
3 to 0	-	0 to 9	unit place	BCD format

# 8.11.3.3 Register Min\_timestp

Table 40. Min\_timestp - minute timestamp register (address 14h) bit description

Bit	Symbol	Value	Place value	Description
7	-	-	-	unused
6 to 4	MINUTE_TIMESTP	0 to 5	ten's place	minute timestamp information coded in
3 to 0		0 to 9	unit place	BCD format

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### 8.11.3.4 Register Hour\_timestp

Table 41. Hour\_timestp - hour timestamp register (address 15h) bit description

Bit	Symbol	Value	Place value	Description			
7 to 6	-	-	-	unused			
12 hour mode[1]							
5	AMPM	0	-	indicates AM			
		1	-	indicates PM			
4	HOUR_TIMESTP	0 to 1	ten's place	hour timestamp information coded in BCD			
3 to 0		0 to 9	unit place	format when in 12 hour mode			
24 ho	ur mode[1]						
5 to 4	HOUR_TIMESTP	0 to 2	ten's place	hour timestamp information coded in BCD			
3 to 0		0 to 9	unit place	format when in 24 hour mode			

<sup>[1]</sup> Hour mode is set by the bit 12\_24 in register Control\_1.

### 8.11.3.5 Register Day\_timestp

Table 42. Day\_timestp - day timestamp register (address 16h) bit description

Bit	Symbol	Value	Place value	Description
7 to 6	-	-	-	unused
5 to 4	DAY_TIMESTP	0 to 3	ten's place	day timestamp information coded in BCD
3 to 0		0 to 9	unit place	format

#### 8.11.3.6 Register Mon\_timestp

Table 43. Mon\_timestp - month timestamp register (address 17h) bit description

Bit	Symbol	Value	Place value	Description
7 to 5	-	-	-	unused
4	MONTH_TIMESTP	0 to 1	ten's place	month timestamp information coded in
3 to 0		0 to 9	unit place	BCD format

#### 8.11.3.7 Register Year\_timestp

Table 44. Year\_timestp - year timestamp register (address 18h) bit description

Bit	Symbol	Value	Place value	Description
7 to 4	YEAR_TIMESTP	0 to 9	ten's place	year timestamp information coded in BCD
3 to 0		0 to 9	unit place	format

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## 8.11.4 Dependency between Battery switch-over and timestamp

The timestamp function depends on the control bit BTSE in register Control\_3:

Table 45. Battery switch-over and timestamp

BTSE	BF	Description
0	-	the battery switch-over does not affect the timestamp registers
1		If a battery switch-over event occurs:
	0	the timestamp registers store the time and date when the switch-over occurs; after this event occurred BF is set logic 1
	1	the timestamp registers are not modified; in this condition subsequent battery switch-over events or falling edges on pin TS are not registered

<sup>[1]</sup> Default value.

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# 8.12 Interrupt output, INT

PCF2129AT has an interrupt output pin INT which is open-drain, active LOW (requiring a pull-up resistor if used). Interrupts may be sourced from different places:

- · second or minute timer
- · watchdog timer
- alarm
- timestamp
- · battery switch-over
- · battery low detection

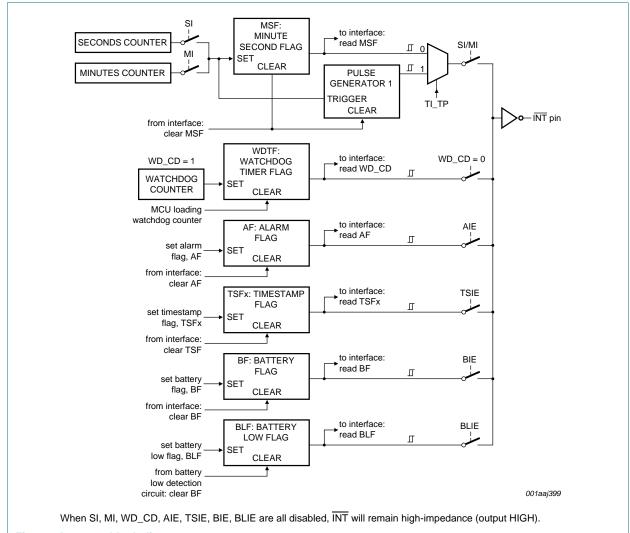


Fig 19. Interrupt block diagram

#### Integrated RTC, TCXO and quartz crystal

The control bit TI\_TP (register Watchdg\_tim\_ctl) is used to configure whether the interrupts generated from the second/minute timer (flag MSF in register Control\_2) are pulsed signals or a permanently active signal. All the other interrupt sources generate a permanently active interrupt signal which follows the status of the corresponding flags. When the interrupt sources are all disabled,  $\overline{INT}$  remains high-impedance.

- The flags MSF, AF, TSFx, and BF can be cleared by command.
- The flag WDTF is read only. How it can be cleared is explained in Section 8.10.5.
- The flag BLF is read only. It is cleared automatically from the battery low detection circuit when the battery is replaced.

#### 8.12.1 Minute and second interrupts

Minute and second interrupts are generated by predefined timers. The timers can be enabled independently from one another by the bits MI and SI in register Control\_1. However, a minute interrupt enabled on top of a second interrupt will not be distinguishable since it will occur at the same time.

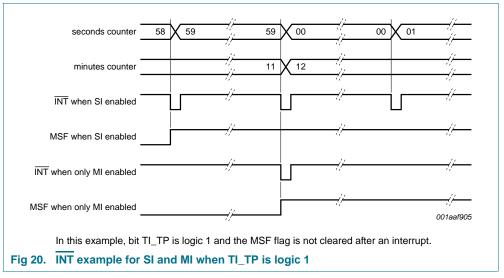
The minute/second flag MSF (register Control\_2) is set logic 1 when either the seconds or the minutes counter increments according to the actually enabled interrupt (see <u>Table 46</u>). The MSF flag can be read and cleared by command.

Table 46. Effect of bits MI and SI on pin INT and bit MSF

MI	SI	Result on INT	Result on MSF
0	0	no interrupt generated	MSF never set
1	0	an interrupt once per minute	MSF set when minutes counter increments
0	1	an interrupt once per second	MSF set when <b>seconds</b> counter increments
1	1	an interrupt once per second	MSF set when <b>seconds</b> counter increments

When MSF is set logic 1:

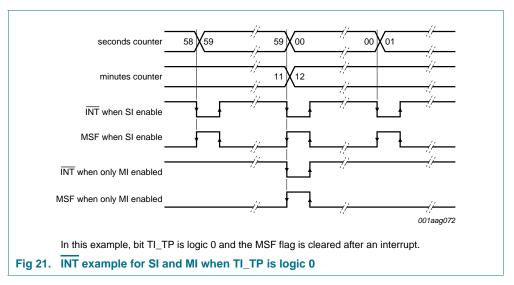
- If TI\_TP is logic 1, the interrupt is generated as a pulsed signal.
- If TI\_TP is logic 0, the interrupt is permanently active signal that remains until MSF is cleared.



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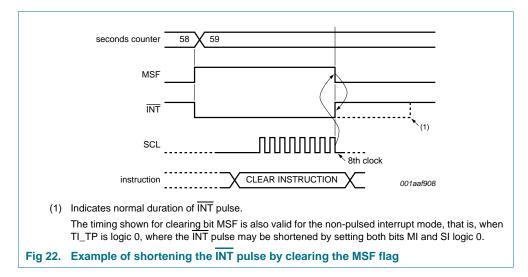
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The pulse generator for the minute/second interrupt operates from an internal 64 Hz clock and generates a pulse of  $\frac{1}{64}$  seconds in duration.

### 8.12.2 INT pulse shortening

If the MSF flag (register Control\_2) is cleared before the end of the  $\overline{\text{INT}}$  pulse, then the  $\overline{\text{INT}}$  pulse is shortened. This allows the source of a system interrupt to be cleared immediately when it is serviced, that is, the system does not have to wait for the completion of the pulse before continuing; see <a href="Figure 22">Figure 22</a>. Instructions for clearing the bit MSF can be found in Section 8.10.5.



#### 8.12.3 Watchdog timer interrupts

The generation of interrupts from the watchdog timer is controlled using the WD\_CD bit (register Watchdg\_tim\_ctl). The interrupt is generated as an active signal which follows the status of the watchdog timer flag WDTF (register Control\_2). No pulse generation is possible for watchdog timer interrupts.

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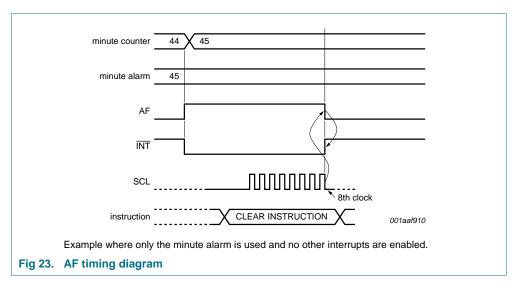
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The interrupt is cleared when the flag WDTF is reset. WDTF is a read only bit and cannot be cleared by command. Instructions for clearing it can be found in <u>Section 8.10.5</u>.

#### 8.12.4 Alarm interrupts

Generation of interrupts from the alarm function is controlled by the bit AIE (register Control\_2). If AIE is enabled, the  $\overline{\text{INT}}$  pin will follow the status of bit AF (register Control\_2). Clearing AF will immediately clear  $\overline{\text{INT}}$ . No pulse generation is possible for alarm interrupts.



#### 8.12.5 Timestamp interrupts

Interrupt generation from the timestamp function is controlled using the TSIE bit (register Control\_2). If TSIE is enabled, the  $\overline{\text{INT}}$  pin follows the status of the flags TSFx. Clearing the flags TSFx immediately clears  $\overline{\text{INT}}$ . No pulse generation is possible for timestamp interrupts.

## 8.12.6 Battery switch-over interrupts

Generation of interrupts from the <u>battery</u> switch-over is controlled by the BIE bit (register Control\_3). If BIE is enabled, the <u>INT</u> pin follows the status of bit BF in register Control\_3 (see <u>Table 45</u>). Clearing BF immediately clears <u>INT</u>. No pulse generation is possible for battery switch-over interrupts.

#### 8.12.7 Battery low detection interrupts

Generation of interrupts from the battery low detection is controlled by the BLIE bit (register Control\_3). If BLIE is enabled, the INT pin will follow the status of bit BLF (register Control\_3). The interrupt is cleared when the battery is replaced (BLF is logic 0) or when bit BLIE is disabled (BLIE is logic 0). BLF is read only and therefore cannot be cleared by command.

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### 8.13 External clock test mode

A test mode is available which allows on-board testing. In this mode, it is possible to set up test conditions and control the operation of the RTC.

The test mode is entered by setting bit EXT\_TEST logic 1 (register Control\_1). Then pin CLKOUT becomes an input. The test mode replaces the internal clock signal (64 Hz) with the signal applied to pin CLKOUT. Every 64 positive edges applied to pin CLKOUT generate an increment of one second.

The signal applied to pin CLKOUT should have a minimum pulse width of 300 ns and a maximum period of 1000 ns. The internal clock, now sourced from CLKOUT, is divided down by a 2<sup>6</sup> divider chain called prescaler (see <u>Table 47</u>). The prescaler can be set into a known state by using bit STOP. When bit STOP is logic 1, the prescaler is reset to 0. STOP must be cleared before the prescaler can operate again.

From a stop condition, the first 1 second increment will take place after 32 positive edges on pin CLKOUT. Thereafter, every 64 positive edges will cause a 1 second increment.

**Remark:** Entry into test mode is not synchronized to the internal 64 Hz clock. When entering the test mode, no assumption as to the state of the prescaler can be made.

#### Operating example:

- 1. Set EXT\_TEST test mode (register Control\_1, EXT\_TEST is logic 1).
- 2. Set bit STOP (register Control\_1, STOP is logic 1).
- 3. Set time registers to desired value.
- 4. Clear STOP (register Control\_1, STOP is logic 0).
- 5. Apply 32 clock pulses to CLKOUT.
- 6. Read time registers to see the first change.
- 7. Apply 64 clock pulses to CLKOUT.
- 8. Read time registers to see the second change.

Repeat 7 and 8 for additional increments.

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### 8.14 STOP bit function

The function of the STOP bit is to allow for accurate starting of the time circuits. STOP will cause the upper part of the prescaler ( $F_9$  to  $F_{14}$ ) to be held in reset and thus no 1 Hz ticks are generated. The time circuits can then be set and will not increment until the STOP bit is released. STOP will not affect the CLKOUT signal but the output of the prescaler in the range of 32 Hz to 1 Hz (see Figure 24).

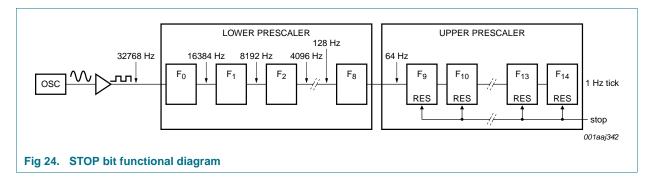
The lower stages of the prescaler,  $F_0$  to  $F_8$ , are not reset and because the I<sup>2</sup>C-bus and the SPI-bus are asynchronous to the crystal oscillator, the accuracy of restarting the time circuits is between 0 and one 64 Hz cycle (0.484375 s and 0.500000 s), see <u>Table 47</u> and <u>Figure 25</u>.

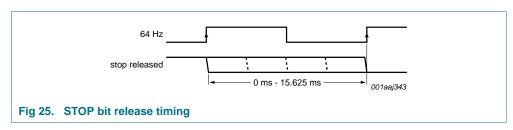
Table 47. First increment of time circuits after stop release

Bit STOP	Prescaler bits[1] F <sub>0</sub> to F <sub>8</sub> - F <sub>9</sub> to F <sub>14</sub>	1 Hz tick	Time hh:mm:ss	Comment
Clock is	running normally			
0	010000111-010100		12:45:12	prescaler counting normally
STOP bit	t is activated by user. F	o to F <sub>8</sub> are not	t reset and valu	es cannot be predicted externally
1	xxxxxxxx-00000		12:45:12	prescaler is reset; time circuits are frozen
New time	e is set by user			
1	xxxxxxxx-000000		08:00:00	prescaler is reset; time circuits are frozen
STOP bit	t is released by user			
0	xxxxxxxx-00000	(O.)	08:00:00	prescaler is now running
0	xxxxxxxx-100000	s 0000 s	08:00:00	
0	xxxxxxxx-100000	.5000	08:00:00	
0	xxxxxxxxx-110000	0.484375 - 0.500000	08:00:00	
:	:	8437	:	
0	111111111-111110	4.0	08:00:00	
0	000000000-000001	1	08:00:01	0 to 1 transition of F <sub>14</sub> increments the time circuits
0	100000000-000001	_   .	08:00:01	
:	:	_	:	
0	111111111-111111	ω	08:00:01	
0	000000000000000		08:00:01	
0	100000000-000000			
:	:		:	
0	111111111-111110	_	08:00:01	
0	000000000-000001		08:00:02	0 to 1 transition of F <sub>14</sub> increments the time circuits
		001aaj479		

<sup>[1]</sup> F<sub>0</sub> is clocked at 32.768 kHz.

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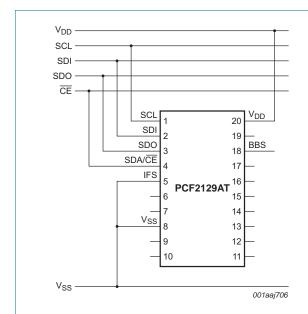
### Integrated RTC, TCXO and quartz crystal

## 9. Interfaces

The PCF2129AT has an  $I^2$ C-bus or SPI-bus interface using the same pins. The selection is done using the interface selection pin IFS (see Table 48).

Table 48. Interface selection input pin IFS

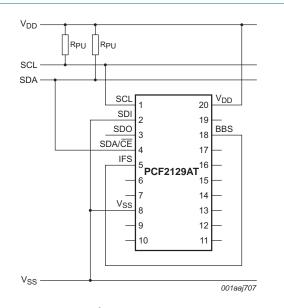
Pin	Connection	Bus interface	Reference
IFS	$V_{SS}$	SPI-bus	Section 9.1
	BBS	I <sup>2</sup> C-bus	Section 9.2



To select the SPI-bus interface, pin IFS has to be connected to pin  $\ensuremath{V_{SS}}.$ 

a. SPI-bus interface selection

Fig 26. Interface selection



To select the I<sup>2</sup>C-bus interface, pin IFS has to be connected to pin BBS.

b. I2C-bus interface selection

### 9.1 SPI-bus interface

Data transfer to and from the device is made by a 3 line SPI-bus (see <u>Table 49</u>). The data lines for input and output are split. The data input and output line can be connected together to facilitate a bidirectional data <u>bus</u> (see <u>Figure 27</u>). The SPI-bus is initialized whenever the chip enable line pin SDA/CE is inactive.

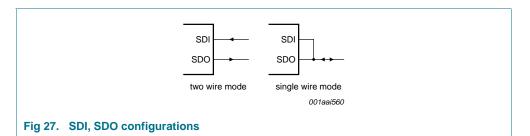


Table 49. Serial interface

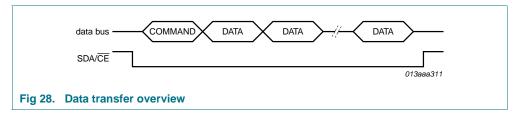
Symbol	Function	Description
SDA/CE		when HIGH, the interface is reset;
	active LOW	input may be higher than V <sub>DD</sub>
SCL	serial clock input	when SDA/CE is HIGH, input may float;
		input may be higher than V <sub>DD</sub>
SDI	serial data input	when SDA/CE is HIGH, input may float;
		input may be higher than V <sub>DD</sub> ;
		input data is sampled on the rising edge of SCL
SDO	serial data output	push-pull output;
		drives from V <sub>SS</sub> to V <sub>BBS</sub> ;
		output data is changed on the falling edge of SCL

<sup>[1]</sup> The chip enable must not be wired permanently LOW.

### 9.1.1 Data transmission

The chip enable signal is used to identify the transmitted data. Each data transfer is a whole byte, with the Most Significant Bit (MSB) sent first.

The transmission is controlled by the active LOW chip enable signal SDA/CE. The first byte transmitted is the command byte. Subsequent bytes will be either data to be written or data to be read (see Figure 28).



The command byte defines the address of the first register to be accessed and the read/write mode. The address counter will auto increment after every access and will reset to zero after the last valid register is accessed. The  $R/\overline{W}$  bit defines if the following bytes will be read or write information.

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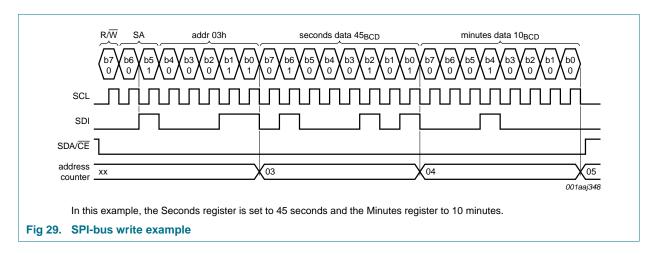
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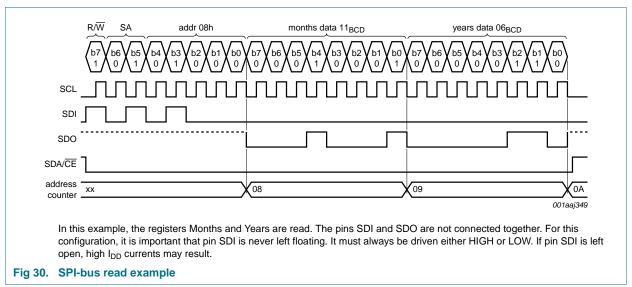
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Table 50. Command byte definition

Bit	Symbol	Value	Description
7 R/W			data read or write selection
		0	write data
		1	read data
6 to 5	SA	01	subaddress;
			other codes will cause the device to ignore data transfer
4 to 0	RA	00h to 1Bh	register address



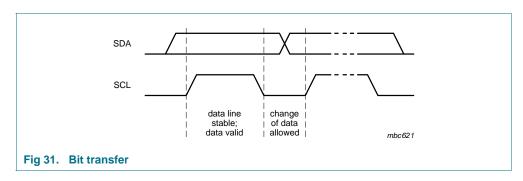


## 9.2 I<sup>2</sup>C-bus interface

The I<sup>2</sup>C-bus is for bidirectional, two-line communication between different ICs or modules. The two lines are a Serial DAta line (SDA) and a Serial CLock line (SCL). Both lines are connected to a positive supply by a pull-up resistor. Data transfer is initiated only when the bus is not busy.

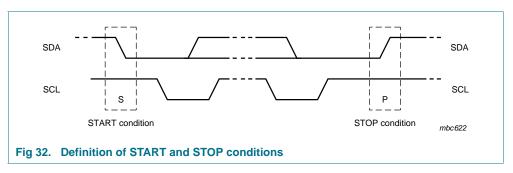
#### 9.2.1 Bit transfer

One data bit is transferred during each clock pulse. The data on the SDA line remains stable during the HIGH period of the clock pulse as changes in the data line at this time are interpreted as control signals (see Figure 31).



#### 9.2.2 START and STOP conditions

Both data and clock lines remain HIGH when the bus is not busy. A HIGH-to-LOW transition of the data line, while the clock is HIGH, is defined as the START condition S. A LOW-to-HIGH transition of the data line while the clock is HIGH is defined as the STOP condition P (see Figure 32).



**Remark:** For the PCF2129AT, a repeated START is not allowed. Therefore a STOP has to be released before the next START.

### 9.2.3 System configuration

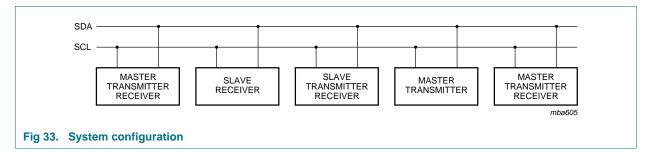
A device generating a message is a transmitter; a device receiving a message is the receiver. The device that controls the message is the master; and the devices which are controlled by the master are the slaves.

The PCF2129AT can act as a slave transmitter and a slave receiver.

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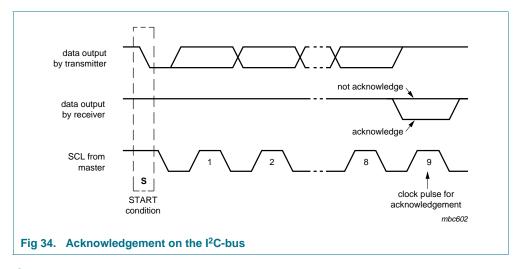


#### 9.2.4 Acknowledge

The number of data bytes transferred between the START and STOP conditions from transmitter to receiver is unlimited. Each byte of eight bits is followed by an acknowledge cycle.

- A slave receiver which is addressed must generate an acknowledge after the reception of each byte.
- Also a master receiver must generate an acknowledge after the reception of each byte that has been clocked out of the slave transmitter.
- The device that acknowledges must pull-down the SDA line during the acknowledge clock pulse, so that the SDA line is stable LOW during the HIGH period of the acknowledge related clock pulse (set-up and hold times must be considered).
- A master receiver must signal an end of data to the transmitter by not generating an
  acknowledge on the last byte that has been clocked out of the slave. In this event, the
  transmitter must leave the data line HIGH to enable the master to generate a STOP
  condition.

Acknowledgement on the I<sup>2</sup>C-bus is illustrated in Figure 34.



#### 9.2.5 I<sup>2</sup>C-bus protocol

After a start condition, a valid hardware address has to be sent to a PCF2129AT device. The appropriate I<sup>2</sup>C-bus slave address is 1010001. The entire I<sup>2</sup>C-bus slave address byte is shown in Table 51.

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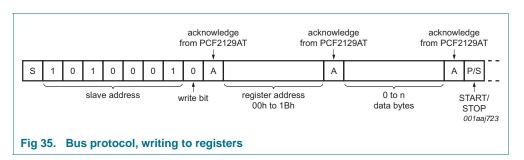
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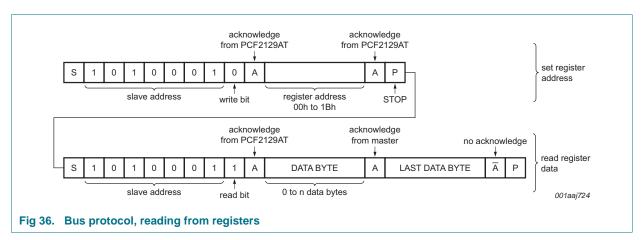
Table 51. I<sup>2</sup>C slave address byte

	Slave address							
Bit	7	6	5	4	3	2	1	0
	MSB							LSB
	1	0	1	0	0	0	1	R/W

The  $R/\overline{W}$  bit defines the direction of the following single or multiple byte data transfer (read is logic 1, write is logic 0).

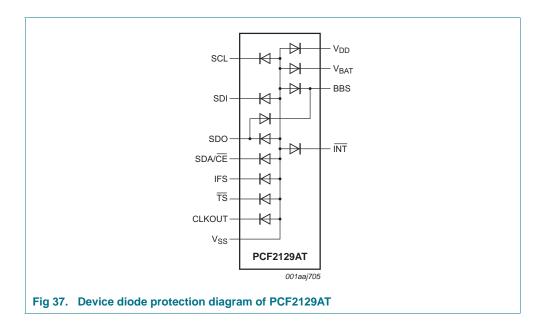
For the format and the timing of the START condition (S), the STOP condition (P), and the acknowledge (A) refer to the I<sup>2</sup>C-bus specification Ref. 11 "UM10204" and the characteristics table (Table 56). In the write mode, a data transfer is terminated by sending either a STOP condition or the START condition of the next data transfer.





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# 10. Internal circuitry



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# 11. Limiting values

Table 52. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DD}$	supply voltage		-0.5	+6.5	V
$I_{DD}$	supply current		-50	+50	mA
Vi	input voltage		-0.5	+6.5	V
I <sub>I</sub>	input current		-10	+10	mA
Vo	output voltage		-0.5	+6.5	V
Io	output current		-10	+10	mA
		at pin SDA/CE	-10	+20	mA
$V_{BAT}$	battery supply voltage		-0.5	+6.5	V
P <sub>tot</sub>	total power dissipation		-	300	mW
$V_{ESD}$	electrostatic discharge	HBM	<u>[1]</u> _	±3500	V
	voltage	CDM	[2] _	±1250	V
I <sub>lu</sub>	latch-up current		[3] _	200	mA
T <sub>stg</sub>	storage temperature		<u>[4]</u> –55	+85	°C
T <sub>amb</sub>	ambient temperature	operating device	-40	+85	°C

<sup>[1]</sup> Pass level; Human Body Model (HBM) according to Ref. 7 "JESD22-A114".

<sup>[2]</sup> Pass level; Charged-Device Model (CDM), according to Ref. 8 "JESD22-C101".

<sup>[3]</sup> Pass level; latch-up testing according to Ref. 9 "JESD78" at maximum ambient temperature (T<sub>amb(max)</sub>).

<sup>[4]</sup> According to the store and transport requirements (see Ref. 12 "UM10569") the devices have to be stored at a temperature of +8  $^{\circ}$ C to +45  $^{\circ}$ C and a humidity of 25  $^{\circ}$ % to 75 %.

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## 12. Static characteristics

Table 53. Static characteristics

 $V_{DD}$  = 1.8 V to 4.2 V;  $V_{SS}$  = 0 V;  $T_{amb}$  = -40 °C to +85 °C, unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit		
Supplies								
$V_{DD}$	supply voltage		<u>[1]</u> 1.8	-	4.2	V		
$V_{BAT}$	battery supply voltage		1.8	-	4.2	V		
V <sub>DD(cal)</sub>	calibration supply voltage		-	3.3	-	V		
$V_{low}$	low voltage		-	1.2	-	V		
I <sub>DD</sub>	supply current	interface active; supplied by V <sub>DD</sub>						
		SPI-bus (f <sub>SCL</sub> = 6.5 MHz)	-	-	800	μΑ		
		$I^2$ C-bus ( $f_{SCL} = 400 \text{ kHz}$ )	-	-	200	μΑ		
		interface inactive ( $f_{SCL} = 0 \text{ F}$ TCR[1:0] = 00 (see <u>Table 9</u>						
		PWRMNG[2:0] = 111 (see TSOFF = 1 (see <u>Table 38</u> COF[2:0] = 111 (see <u>Table</u>	on page 35);					
		V <sub>DD</sub> = 2.0 V	-	500	-	nΑ		
		$V_{DD} = 3.3 \text{ V}$	-	700	1500	nA		
		V <sub>DD</sub> = 4.2 V	-	800	-	nA		
		PWRMNG[2:0] = 111 (see <u>Table 14 on page 14</u> ); TSOFF = 1 (see <u>Table 38 on page 35</u> ); COF[2:0] = 000 (see <u>Table 11 on page 12</u> )						
		$V_{DD} = 2.0 \text{ V}$	-	600	-	nA		
		$V_{DD} = 3.3 \text{ V}$	-	850	-	nA		
		$V_{DD} = 4.2 \text{ V}$	-	1050	-	nA		
		PWRMNG[2:0] = 000 (see TSOFF = 0 (see Table 38 COF[2:0] = 111 (see Table	on page 35);					
		$V_{DD}$ or $V_{BAT} = 2.0 \text{ V}$	[3] _	1800	-	nA		
		$V_{DD}$ or $V_{BAT} = 3.3 \text{ V}$	[3] _	2150	-	nA		
		$V_{DD}$ or $V_{BAT} = 4.2 \text{ V}$	[3] _	2350	3500	nA		
		PWRMNG[2:0] = 000 (see TSOFF = 0 (see <u>Table 38</u> COF[2:0] = 000 (see <u>Table</u>	on page 35);					
		$V_{DD}$ or $V_{BAT} = 2.0 \text{ V}$	[3] _	1900	-	nA		
		$V_{DD}$ or $V_{BAT} = 3.3 \text{ V}$	[3]	2300	-	nΑ		
		$V_{DD}$ or $V_{BAT} = 4.2 \text{ V}$	[3] _	2600	-	nΑ		
I <sub>L(bat)</sub>	battery leakage current	$V_{DD}$ is active supply; $V_{BAT} = 3.0 \text{ V}$	-	50	100	nA		
Power ma	nagement							
$V_{th(sw)bat}$	battery switch threshold voltage		-	2.5	-	V		
V <sub>th(bat)low</sub>	low battery threshold voltage			2.5		V		

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## Integrated RTC, TCXO and quartz crystal

Table 53. Static characteristics ...continued  $V_{DD} = 1.8 \text{ V to } 4.2 \text{ V; } V_{SS} = 0 \text{ V; } T_{amb} = -40 \text{ °C to } +85 \text{ °C, unless otherwise specified.}$ 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Inputs[4]						
VI	input voltage		-0.5	-	$V_{DD} + 0.5$	V
V <sub>IL</sub>	LOW-level input voltage		-	-	$0.25V_{DD}$	V
		$T_{amb}$ = -20 °C to +85 °C; $V_{DD}$ > 2.0 V	-	-	$0.3V_{DD}$	V
V <sub>IH</sub>	HIGH-level input voltage		$0.7V_{DD}$	-	-	V
I <sub>LI</sub>	input leakage current	$V_I = V_{DD}$ or $V_{SS}$	-	0	-	μΑ
		post ESD event	<b>–1</b>	-	+1	μΑ
C <sub>i</sub>	input capacitance		<u>[5]</u> _	-	7	pF
Outputs						
Vo	output voltage	on pins CLKOUT, INT, referring to external pull-up	-0.5	-	5.5	V
VO		on pin SDO	-0.5	-	$V_{BBS} + 0.5$	V
l <sub>OL</sub>	LOW-level output current	output sink current; V <sub>OL</sub> = 0.4 V				
		on pin SDA/CE	<u>6</u> 3	17	-	mΑ
		on all other outputs	1.0	-	-	mΑ
Іон	HIGH-level output current	output source current; on pin SDO; $V_{OH} = 3.8 \text{ V}$ ; $V_{DD} = 4.2 \text{ V}$	1.0	-	-	mA
I <sub>LI</sub>	output leakage current	$V_O = V_{DD}$ or $V_{SS}$	-	0	-	μΑ
		post ESD event	<b>–1</b>	-	+1	μΑ

<sup>[1]</sup> For reliable oscillator start-up at power-on:  $V_{DD(po)min} = V_{DD(min)} + 0.3 \text{ V}$ .

<sup>[2]</sup> Timer source clock =  $\frac{1}{60}$  Hz, level of pins SDA/ $\overline{\text{CE}}$ , SDI, and SCL is  $V_{DD}$  or  $V_{SS}$ .

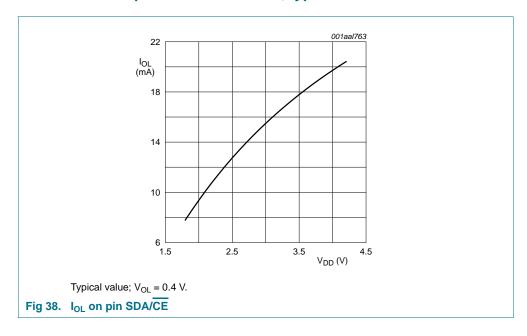
<sup>[3]</sup> When the device is supplied by the V<sub>BAT</sub> pin instead of the V<sub>DD</sub> pin, the current values for I<sub>BAT</sub> will be as specified for I<sub>DD</sub> under the same conditions.

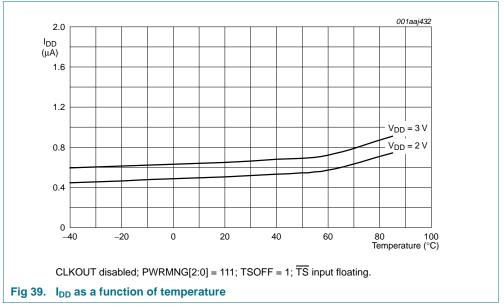
<sup>[4]</sup> The I<sup>2</sup>C-bus interface of PCF2129AT is 5 V tolerant.

<sup>[5]</sup> Tested on sample basis.

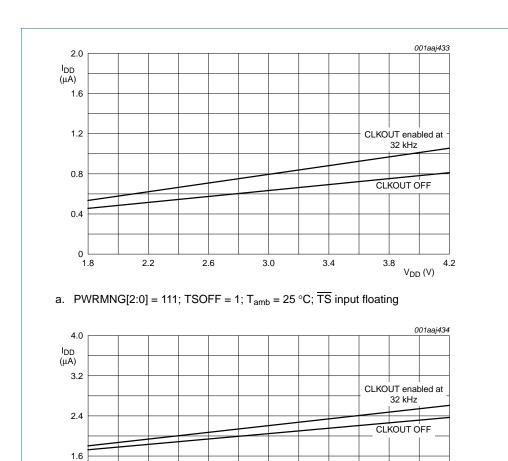
<sup>[6]</sup> For further information, see Figure 38.

# 12.1 Current consumption characteristics, typical





## Integrated RTC, TCXO and quartz crystal



b. PWRMNG[2:0] = 000; TSOFF = 0;  $T_{amb}$  = 25 °C;  $\overline{TS}$  input floating

Fig 40.  $I_{DD}$  as a function of  $V_{DD}$ 

0 L 1.8

 $V_{DD}(V)$ 

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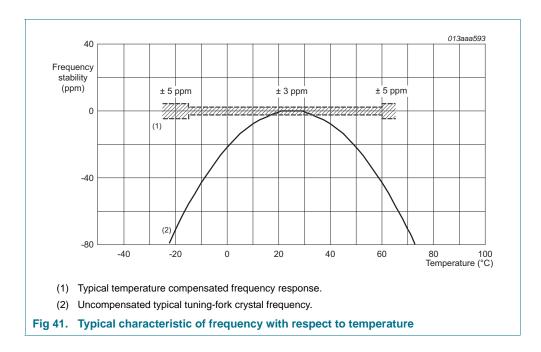
# 12.2 Frequency characteristics

Table 54. Frequency characteristics

 $V_{DD}$  = 1.8 V to 4.2 V;  $V_{SS}$  = 0 V;  $T_{amb}$  = +25 °C, unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f <sub>o</sub>	output frequency	on pin CLKOUT; $V_{DD}$ or $V_{BAT} = 3.3 \text{ V}$ ; COF[2:0] = 000; AO[3:0] = 1000	-	32.768	-	kHz
Δf/f	frequency stability	$V_{DD}$ or $V_{BAT} = 3.3 \text{ V}$				
		$T_{amb} = -15  ^{\circ}\text{C} \text{ to } +60  ^{\circ}\text{C}$	[1][2] -	±3	±5	ppm
		$T_{amb} = -25 ^{\circ}\text{C} \text{ to } -15 ^{\circ}\text{C}$ and $T_{amb} = +60 ^{\circ}\text{C} \text{ to } +65 ^{\circ}\text{C}$	<u>[1][2]</u> -	±5	±10	ppm
$\Delta f_{xtal}/f_{xtal}$	relative crystal frequency variation	crystal aging, first year; V <sub>DD</sub> or V <sub>BAT</sub> = 3.3 V	<u>[3]</u> -	-	±3	ppm
Δf/ΔV	frequency variation with voltage	on pin CLKOUT	-	±1	-	ppm/V

- [1]  $\pm 1$  ppm corresponds to a time deviation of  $\pm 0.0864$  seconds per day.
- [2] Only valid if CLKOUT frequencies are not equal to 32.768 kHz or if CLKOUT is disabled.
- [3] Not production tested. Effects of reflow solder not included (see Ref. 3 "AN10857").



### Integrated RTC, TCXO and quartz crystal

# 13. Dynamic characteristics

## 13.1 SPI-bus timing characteristics

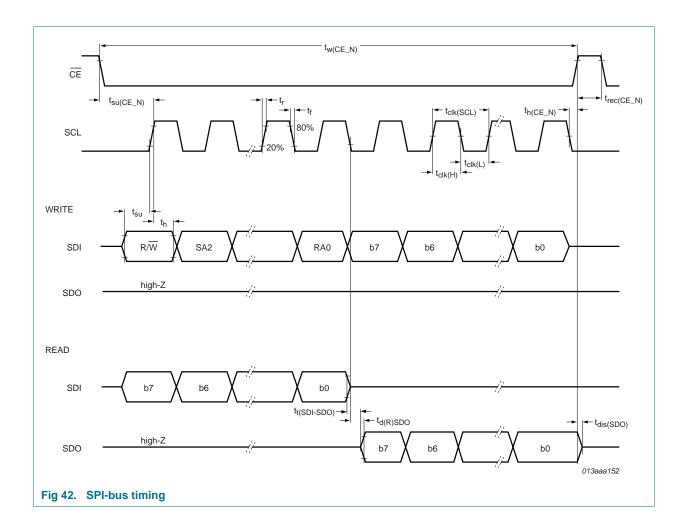
#### Table 55. SPI-bus characteristics

 $V_{DD}$  = 1.8 V to 4.2 V;  $V_{SS}$  = 0 V;  $T_{amb}$  = -40 °C to +85 °C, unless otherwise specified. All timing values are valid within the operating supply voltage at ambient temperature and referenced to  $V_{IL}$  and  $V_{IH}$  with an input voltage swing of  $V_{SS}$  to  $V_{DD}$  (see Figure 42).

Symbol	Parameter	Conditions	V <sub>DD</sub> = 1	.8 V	$V_{DD} = 4$	$V_{DD} = 4.2 \text{ V}$	
			Min	Max	Min	Max	
Pin SCL			'	'		'	
f <sub>clk(SCL)</sub>	SCL clock frequency		-	2.0	-	6.5	MHz
t <sub>SCL</sub>	SCL time		800	-	140	-	ns
t <sub>clk(H)</sub>	clock HIGH time		100	-	70	-	ns
$t_{clk(L)}$	clock LOW time		400	-	70	-	ns
t <sub>r</sub>	rise time	for SCL signal	-	100	-	30	ns
t <sub>f</sub>	fall time	for SCL signal	-	100	-	30	ns
Pin SDA/C	E						
$t_{\text{su}(\text{CE}\_\text{N})}$	CE_N set-up time		60	-	30	-	ns
$t_{h(CE\_N)}$	CE_N hold time		40	-	25	-	ns
$t_{\text{rec}(\text{CE}_N)}$	CE_N recovery time		100	-	30	-	ns
$t_{w(CE\_N)}$	CE_N pulse width		-	0.99	-	0.99	s
Pin SDI							
t <sub>su</sub>	set-up time	set-up time for SDI data	70	-	20	-	ns
t <sub>h</sub>	hold time	hold time for SDI data	70	-	20	-	ns
Pin SDO							
$t_{d(R)SDO}$	SDO read delay time	$C_L = 50 pF$	-	225	-	55	ns
t <sub>dis(SDO)</sub>	SDO disable time	[1]	-	90	-	25	ns
$t_{t(SDI\text{-}SDO)}$	transition time from SDI to SDO	to avoid bus conflict	0	-	0	-	ns

<sup>[1]</sup> No load value; bus will be held up by bus capacitance; use RC time constant with application values.

# Integrated RTC, TCXO and quartz crystal



## 13.2 I<sup>2</sup>C-bus timing characteristics

#### Table 56. I<sup>2</sup>C-bus characteristics

All timing characteristics are valid within the operating supply voltage and ambient temperature range and reference to 30 % and 70 % with an input voltage swing of  $V_{SS}$  to  $V_{DD}$  (see Figure 43).

Symbol	Parameter		Standa	rd mode	Fast-mode	(Fm)	Unit
			Min	Max	Min	Max	
Pin SCL			1	'		'	
f <sub>SCL</sub>	SCL clock frequency	<u>[1]</u>	0	100	0	400	kHz
$t_{LOW}$	LOW period of the SCL clock		4.7	-	1.3	-	μS
t <sub>HIGH</sub>	HIGH period of the SCL clock		4.0	-	0.6	-	μS
Pin SDA	/CE						
t <sub>SU;DAT</sub>	data set-up time		250	-	100	-	ns
t <sub>HD;DAT</sub>	data hold time		0	-	0	-	ns
Pins SC	L and SDA/CE						
t <sub>BUF</sub>	bus free time between a STOP and START condition		4.7	-	1.3	-	μS
t <sub>SU;STO</sub>	set-up time for STOP condition		4.0	-	0.6	-	μS
t <sub>HD;STA</sub>	hold time (repeated) START condition		4.0	-	0.6	-	μS
t <sub>SU;STA</sub>	set-up time for a repeated START condition		4.7	-	0.6	-	μS
t <sub>r</sub>	rise time of both SDA and SCL signals	[2][3][4]	-	1000	20 + 0.1C <sub>b</sub>	300	ns
t <sub>f</sub>	fall time of both SDA and SCL signals	[2][3][4]	-	300	20 + 0.1C <sub>b</sub>	300	ns
t <sub>VD;ACK</sub>	data valid acknowledge time	<u>[5]</u>	0.1	3.45	0.1	0.9	μS
t <sub>VD;DAT</sub>	data valid time	[6]	300	-	75	-	ns
t <sub>SP</sub>	pulse width of spikes that must be suppressed by the input filter	[7]	-	50	-	50	ns

<sup>[1]</sup> The minimum SCL clock frequency is limited by the bus time-out feature which resets the serial bus interface if either the SDA or SCL is held LOW for a minimum of 25 ms. The bus time-out feature must be disabled for DC operation.

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**Product data sheet** 

<sup>[2]</sup> A master device must internally provide a hold time of at least 300 ns for the SDA signal (refer to the V<sub>IL</sub> of the SCL signal) in order to bridge the undefined region of the falling edge of SCL.

<sup>[3]</sup> C<sub>b</sub> is the total capacitance of one bus line in pF.

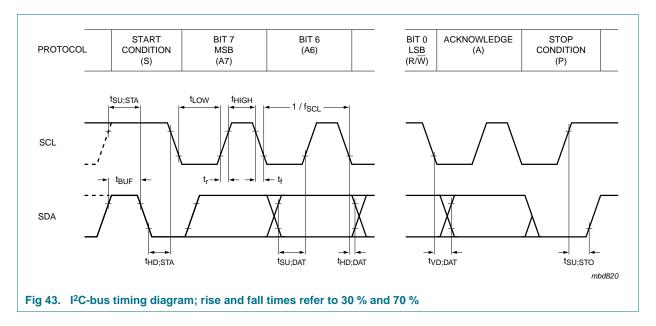
<sup>[4]</sup> The maximum t<sub>f</sub> for the SDA and SCL bus lines is 300 ns. The maximum fall time for the SDA output stage, t<sub>f</sub> is 250 ns. This allows series protection resistors to be connected between the SDA/CE pin, the SCL pin, and the SDA/SCL bus lines without exceeding the maximum t<sub>f</sub>.

<sup>[5]</sup>  $t_{VD;ACK}$  is the time of the acknowledgement signal from SCL LOW to SDA (out) LOW.

<sup>[6]</sup> t<sub>VD:DAT</sub> is the minimum time for valid SDA (out) data following SCL LOW.

 $<sup>\</sup>cite{Model}$  Input filters on the SDA and SCL inputs suppress noise spikes of less than 50 ns.

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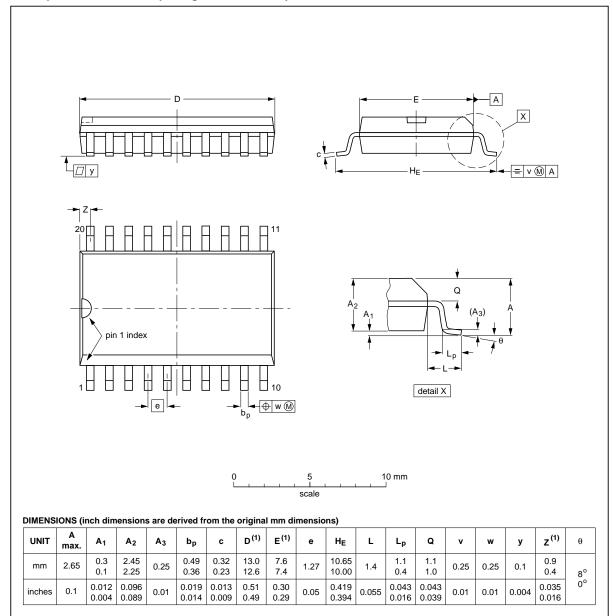
# 14. Application information

For information about application configuration, see Ref. 3 "AN10857".

# 15. Package outline

#### SO20: plastic small outline package; 20 leads; body width 7.5 mm

SOT163-1



#### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION ISSUE DA	ISSUE DATE
SOT163-1	075E04	MS-013			<del>-99-12-27</del> 03-02-19

Fig 44. Package outline SOT163-1 (SO20)

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# 16. Packing information

## 16.1 Carrier tape information

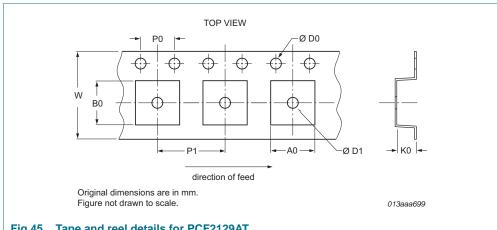


Fig 45. Tape and reel details for PCF2129AT

Table 57. Carrier tape dimensions of PCF2129AT

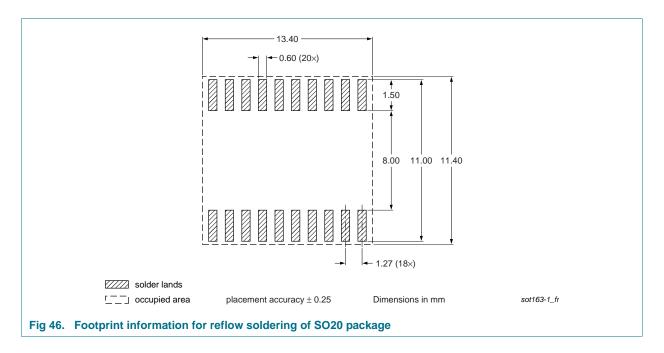
Symbol	Description	Value	Unit
Compartments			
A0	pocket width in x direction	10.8 to 10.9	mm
B0	pocket width in y direction	13.3 to 13.4	mm
K0	pocket depth	2.70 to 2.85	mm
P1	pocket hole pitch	12.0	mm
D1	pocket hole diameter	1.5 to 2.05	mm
Overall dimens	ions		
W	tape width	24.0	mm
D0	sprocket hole diameter	1.5 to 1.55	mm
P0	sprocket hole pitch	4.0	mm

# 17. Soldering

For information about soldering, see Ref. 3 "AN10857".

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# 18. Footprint information



# Integrated RTC, TCXO and quartz crystal

# 19. Abbreviations

Table 58. Abbreviations

Acronym	Description
AM	Ante Meridiem
BCD	Binary Coded Decimal
CDM	Charged Device Model
CMOS	Complementary Metal-Oxide Semiconductor
DC	Direct Current
GPS	Global Positioning System
HBM	Human Body Model
I <sup>2</sup> C	Inter-Integrated Circuit
IC	Integrated Circuit
LSB	Least Significant Bit
MCU	Microcontroller Unit
MM	Machine Model
MSB	Most Significant Bit
PM	Post Meridiem
POR	Power-On Reset
PORO	Power-On Reset Override
PPM	Parts Per Million
RC	Resistance-Capacitance
RTC	Real Time Clock
SCL	Serial CLock line
SDA	Serial DAta line
SPI	Serial Peripheral Interface
SRAM	Static Random Access Memory
TCXO	Temperature Compensated Xtal Oscillator
Xtal	crystal

#### Integrated RTC, TCXO and quartz crystal

### 20. References

- [1] AN10365 Surface mount reflow soldering description
- [2] AN10853 Handling precautions of ESD sensitive devices
- [3] AN10857 Application and soldering information for PCF2127A and PCF2129A TCXO RTC
- [4] IEC 60134 Rating systems for electronic tubes and valves and analogous semiconductor devices
- [5] IEC 61340-5 Protection of electronic devices from electrostatic phenomena
- [6] IPC/JEDEC J-STD-020D Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices
- [7] JESD22-A114 Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)
- [8] JESD22-C101 Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components
- [9] JESD78 IC Latch-Up Test
- [10] JESD625-A Requirements for Handling Electrostatic-Discharge-Sensitive (ESDS) Devices
- [11] UM10204 I<sup>2</sup>C-bus specification and user manual
- [12] UM10569 Store and transport requirements

# Integrated RTC, TCXO and quartz crystal

# 21. Revision history

### Table 59. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PCF2129AT v.5	20130212	Product data sheet	-	PCF2129AT v.4
Modifications:	<ul> <li>Improved des</li> </ul>	scription of V <sub>BAT</sub> pin in <u>Table 4</u>		
PCF2129AT v.4	20121107	Product data sheet	-	PCF2129AT v.3
PCF2129AT v.3	20121004	Product data sheet	-	PCF2129A v.2
PCF2129A v.2	20100507	Product data sheet	-	PCF2129A v.1
PCF2129A v.1	20100113	Product data sheet	-	-

#### Integrated RTC, TCXO and quartz crystal

# 22. Legal information

#### 22.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

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# Integrated RTC, TCXO and quartz crystal

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